

# RECAP: BEAM DIAGNOSTICS

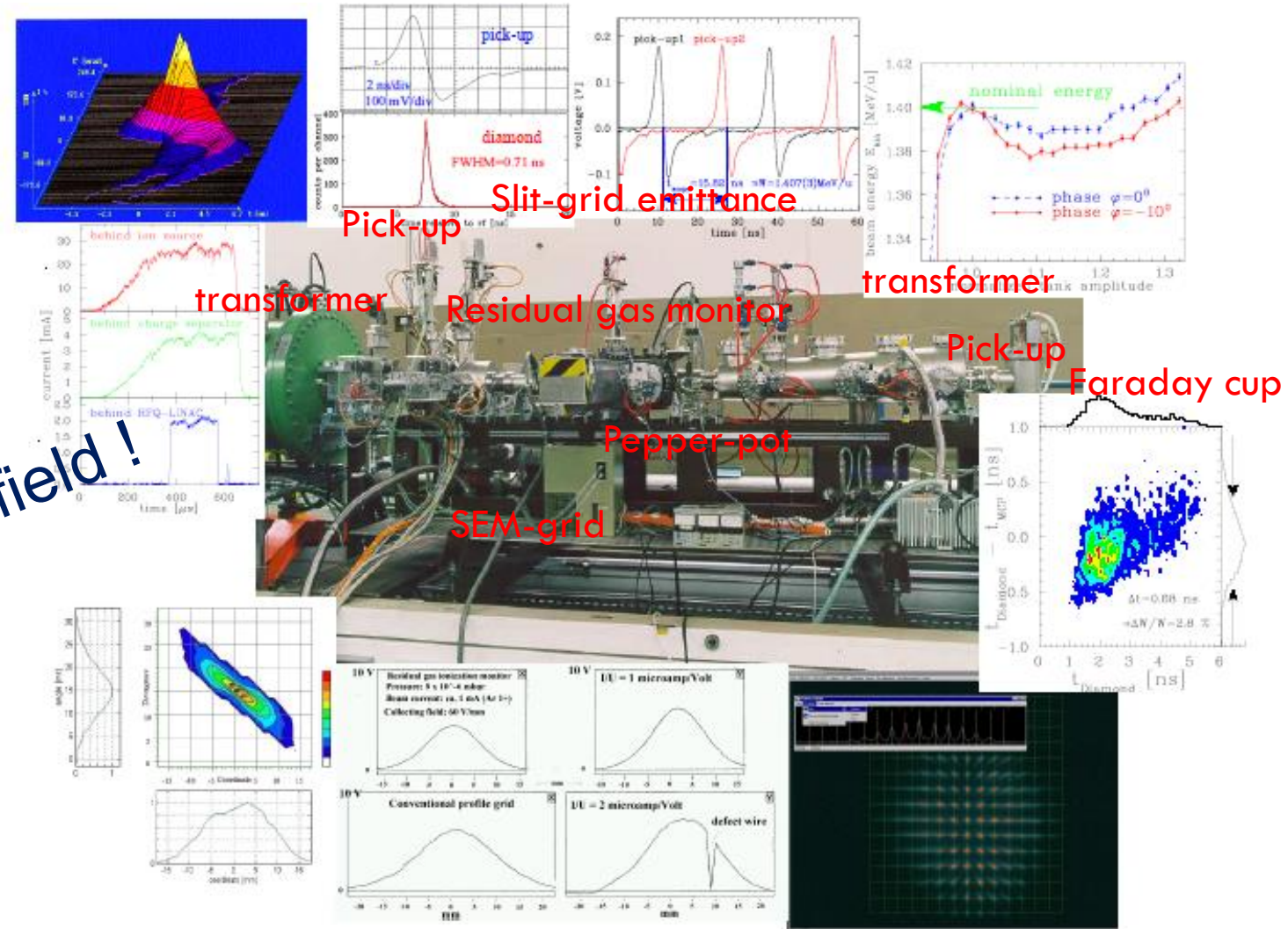
- Why beam Diagnostics?
- Challenges in Diagnostics?
- Instrumentation type
  - ▣ Beam position monitoring
  - ▣ Beam profile monitoring
  - ▣ Emittance measurement
  - ▣ Beam current monitoring
  - ▣ Beam energy monitoring
  - ▣ Beam halo monitoring

- Essential for any accelerator
- ‘Organ of sense’
- Deal with real beam with imperfections
- Three categories
  - ▣ Reliable, quick measurements for general functionality, e.g. current transformer
  - ▣ For a daily check of performance and stability, e.g. profile determination
  - ▣ Complex instrumentation, e.g. Emittance measurement

Beam quantity		LINAC, transfer line	Synchrotron
current $I$	<i>general</i>	transformer (dc, pulsed) Faraday cup	transformer (dc)
	<i>special</i>	particle detector (Scint. IC, SEM)	normalized pick-up signal
position $\bar{x}$	<i>general</i>	pick-up	pick-up
	<i>special</i>	using profile measurement	cavity excitation ( $e^-$ )
profile $x_{width}$	<i>general</i>	SEM-grid, wire scanner viewing screen, OTR-screen	residual gas monitor synch. radiation ( $e^-$ ) wire scanner
	<i>special</i>	grid with ampl. (MWPC)	
trans. emittance $\epsilon_{trans}$	<i>general</i>	slit grid	residual gas monitor
	<i>special</i>	quadrupole scan pepper-pot	wire scanner transverse Schottky pick-up wire scanner
momentum $p$ and $\Delta p/p$	<i>general</i>	pick-up (TOF)	pick-up
	<i>special</i>	magn. spectrometer	Schottky noise pick-up
bunch width $\Delta\varphi$	<i>general</i>	pick-up	pick-up
	<i>special</i>	particle detector secondary electrons	wall current monitor streak camera ( $e^-$ )
long. emittance $\epsilon_{long}$	<i>general</i>	magn. spectrometer	
	<i>special</i>	buncher scan TOF application	pick-up + tomography
tune, chromaticity $Q, \xi$	<i>general</i>	—	exciter + pick-up (BTF)
	<i>special</i>	—	transverse Schottky pick-up
beam loss $r_{loss}$	<i>general</i>	particle detector	
polarization $P$	<i>general</i>	particle detector	
	<i>special</i>	Compton scattering with laser	
luminosity $\mathcal{L}$	<i>general</i>	particle detector	

- Material sciences
- Thermodynamics
- Electro-Magnetism
- Optics
- laser technology
- Mechanics
- Electronics
- Nuclear Physics
- Vacuum science
- ...

Multi-disciplinary field !

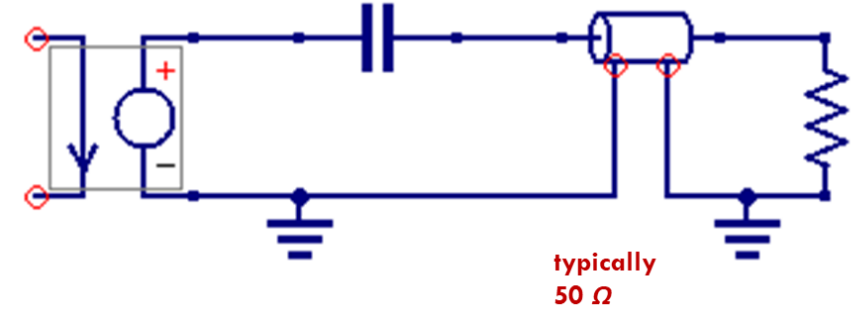
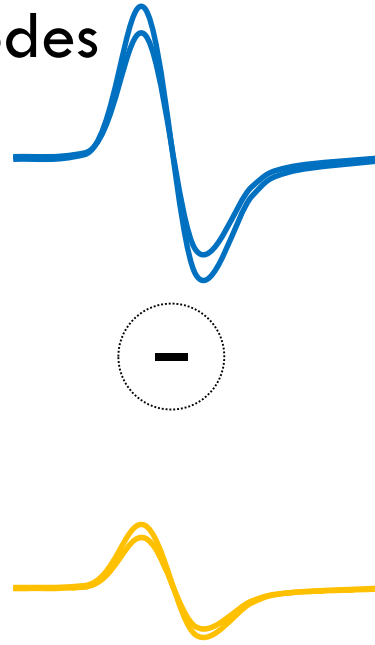
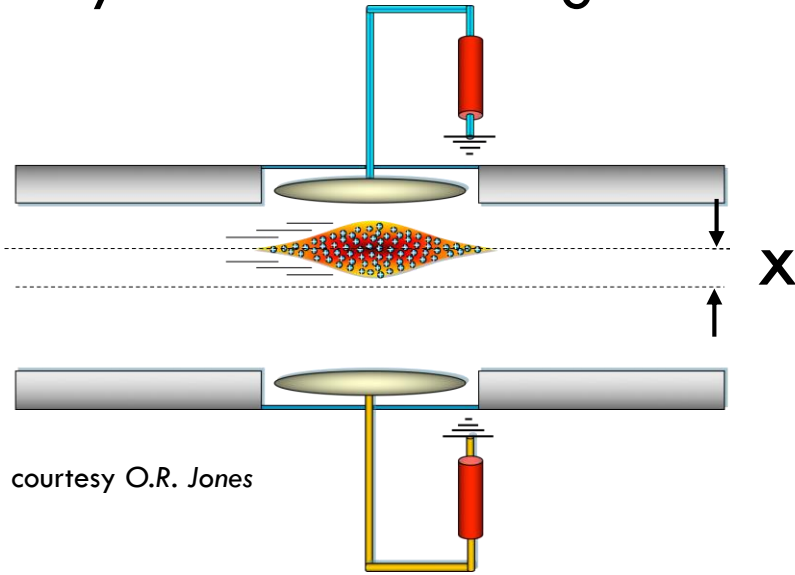


A picture of the mobile test bench including some measurements, as provided for the commissioning of the high current injector at GSI in 1999.

- Better resolution (time/space)
- (single) photon resolution
- Improved radiation hardness
- invasive
- Able to cover variety of beams

# Beam Position Monitoring

- The Capacitive Pickups are based on symmetry
  - ▣ The beam displacement  $x$  is detected by a pair of symmetrical arrange electrodes



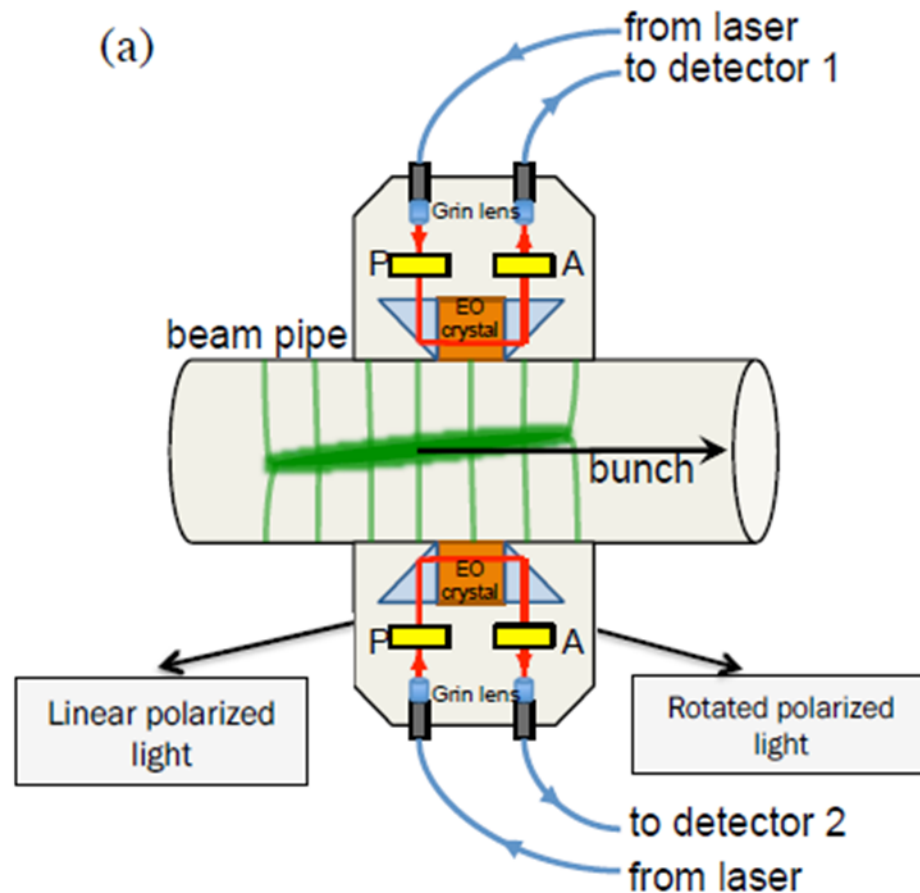
Examples:

- Shoebox type
- Buttons
- Striplines

$$x = k \cdot \frac{\Delta U}{\Sigma U} + \delta,$$

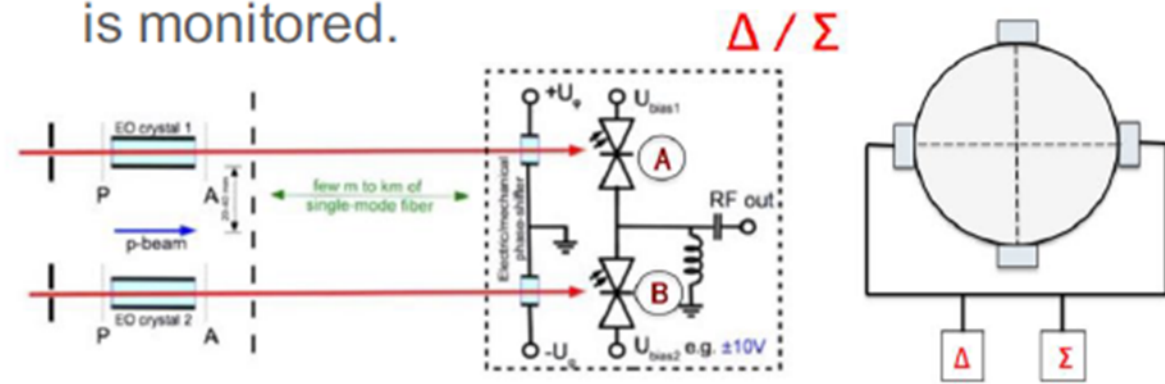


Aim to develop fast, intra-bunch diagnostics to monitor crab-rotation of bunches.



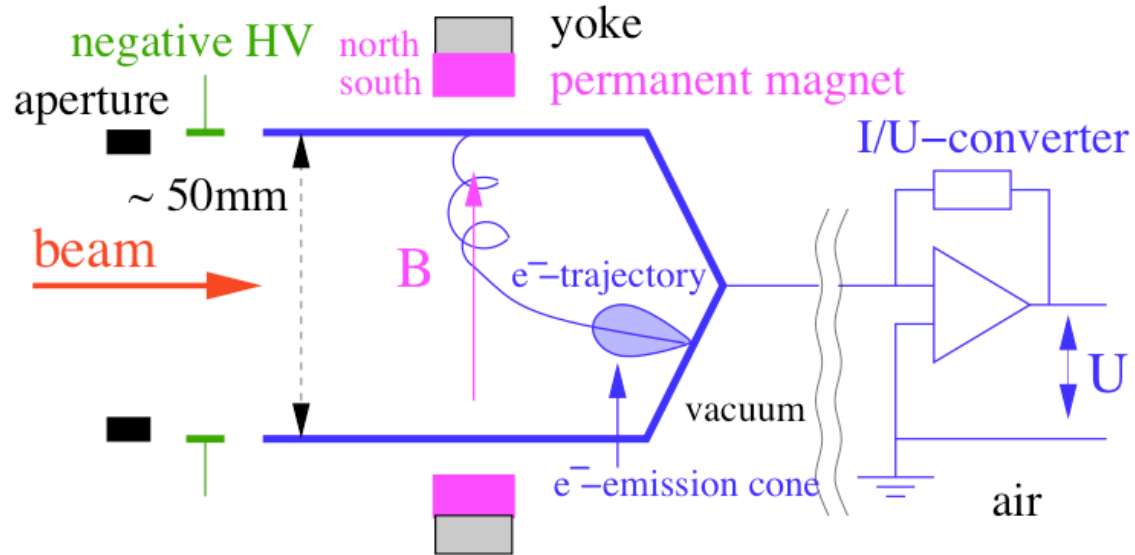
courtesy S. Gibson

- Replace pick-ups in a button BPM with electro-optic crystals.
- The electric field from a passing bunch induces a **polarization change** of light through the crystal.
- Fibre-coupled design with laser and detectors 160 m away from accelerator tunnel.
- Transverse position along the 1ns LHC bunch is monitored.

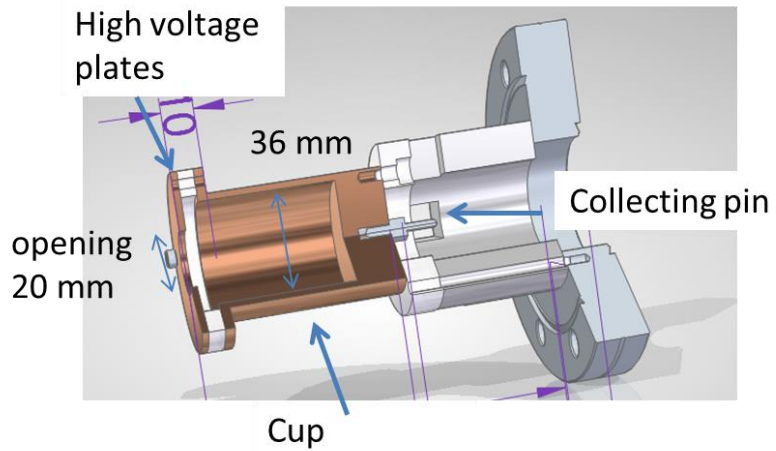
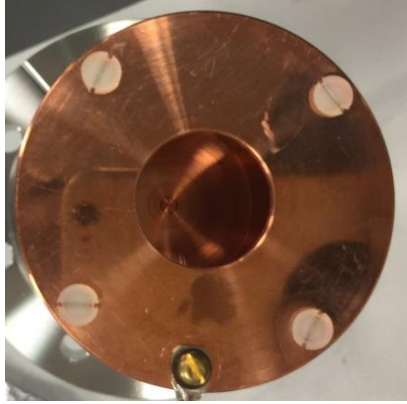
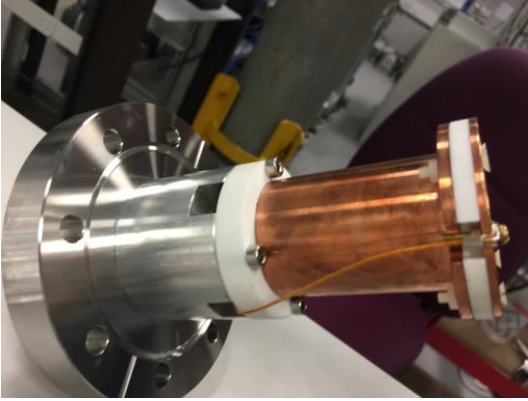




# Beam Current Monitoring



- The Faraday Cup destructively intercepts the beam
- DC coupled! (With just a resistor the signal is  $V_{out} = I_{beam} * R$ )
- Low current measurements possible e.g., USR fA!
- Problem with secondary electrons:
  - ▣ Use long cup or voltage suppression or magnetic field
- If not properly terminated -> very high voltage (beam potential)
- Must process beam power



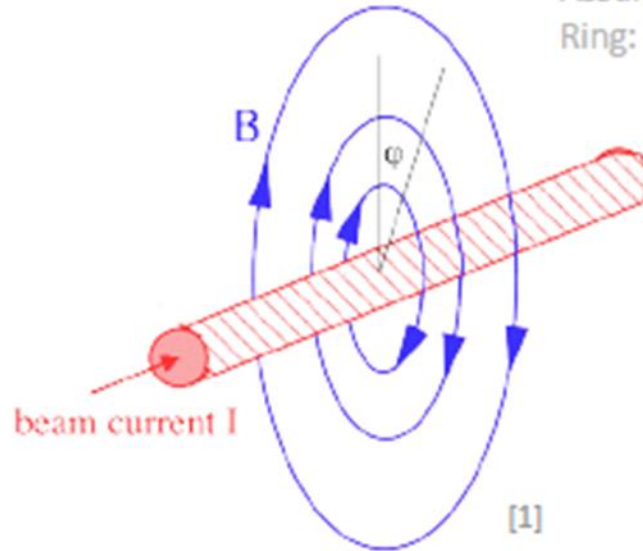
Simple faraday cup in my lab



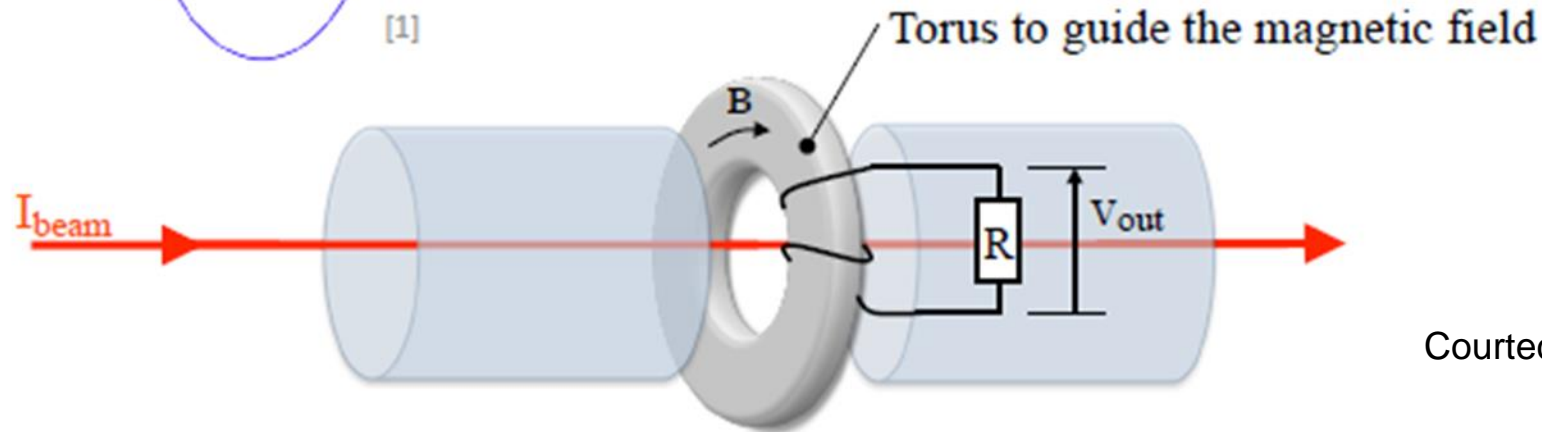
For higher intensities  
water cooling may be needed

Measure the beam current through the magnetic field of the beam.

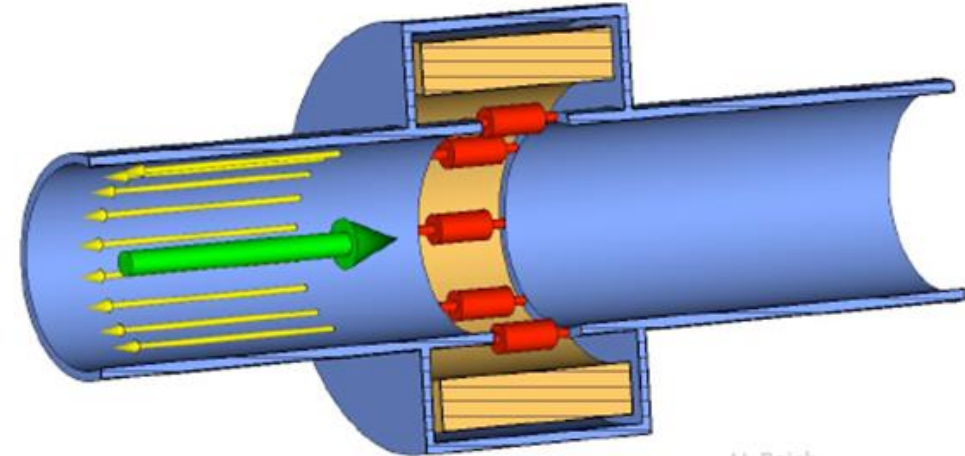
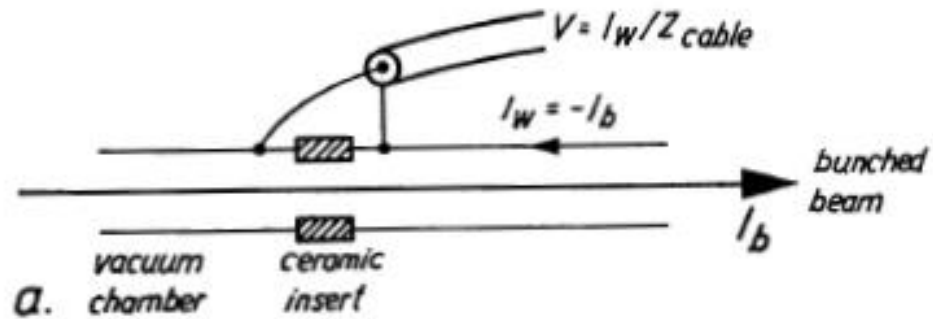
Assume the beam is long enough to be regarded as a line current. E.g. SNS  
Ring: 250 meters for 1usec



Line current field: 
$$\vec{B} = \mu \cdot \frac{I_{beam}}{2\pi r} \vec{a}_\phi$$



Courtesy: W. Blokland

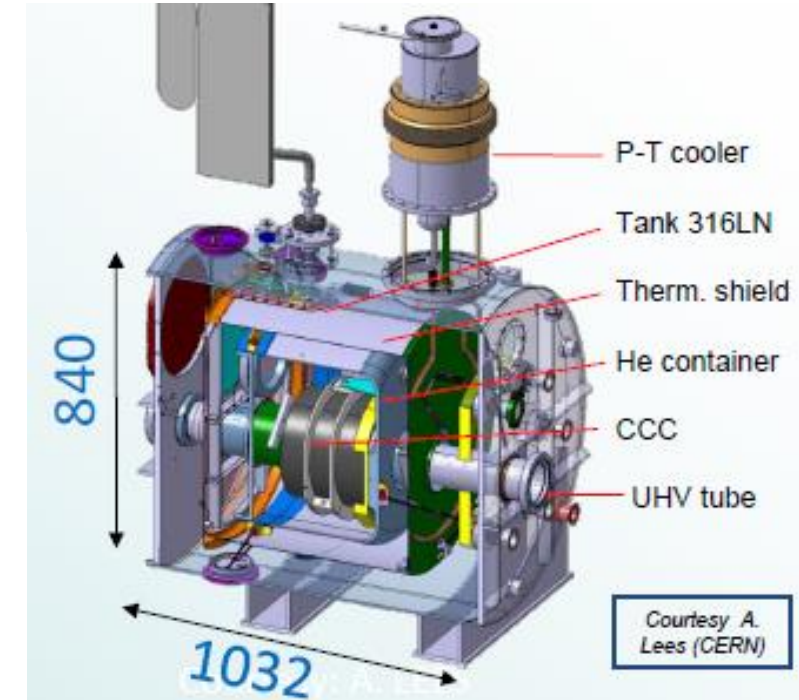
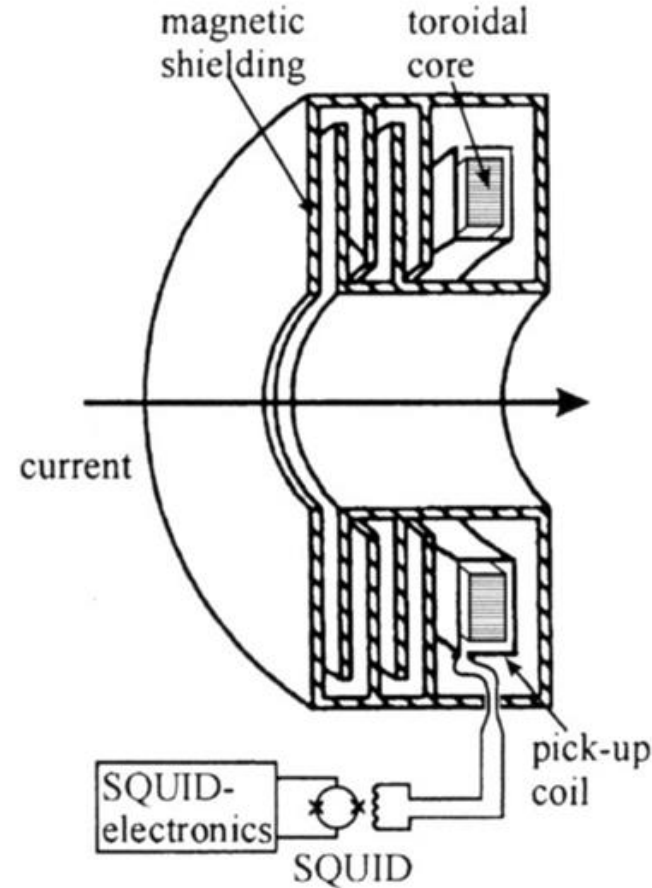


- The image current accompany the beam current.
- A voltage proportional to beam current can be measured across the resistors
- Also the noise issue will limit the resolution



- Non-destructive measurement device for low intensity beams (between 1 nA to 10  $\mu$ A)

- The CCC consists of:
  - ▣ Cryogenic device
  - ▣ SC pickup coil,
  - ▣ Highly efficient SC shield,
  - ▣ High performance SQUID measurement system.



Courtesy A. Lees (CERN)

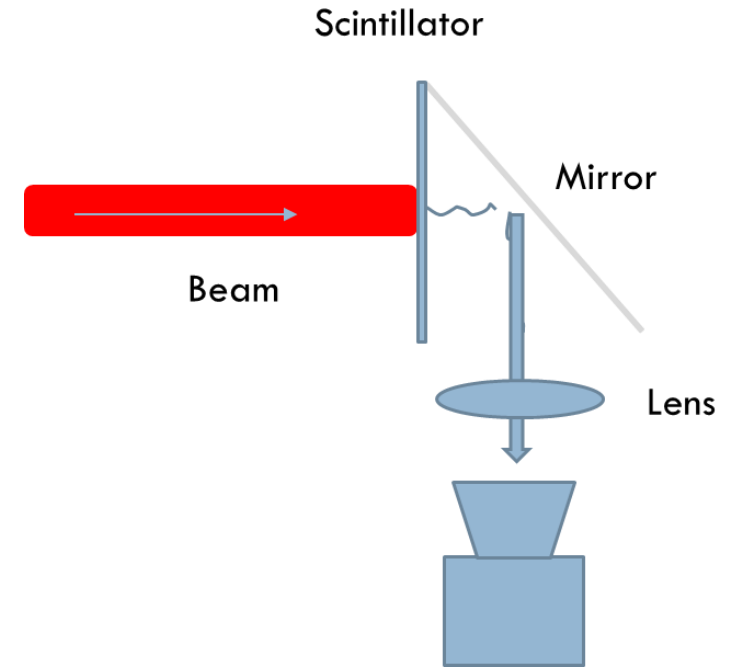
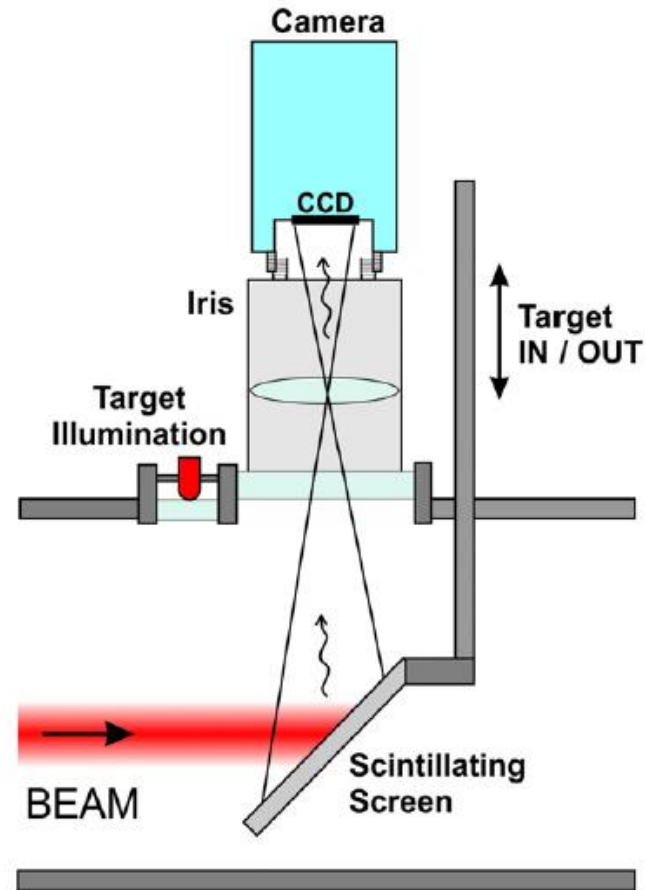


Courtesy R. Jones, M. Fernandes (CERN)



# Beam Profile Monitoring

- Simply
- Cheap
- Effective

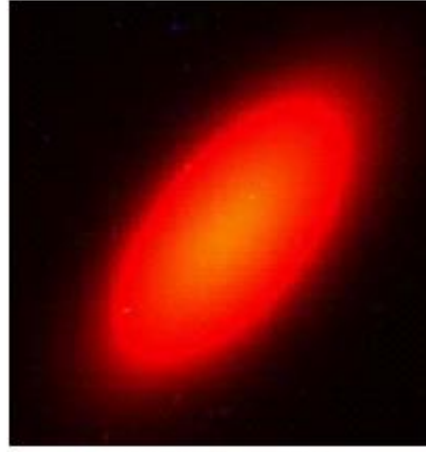


Credit: B. Walasek-Höhne, GSI and G. Kube, DESY

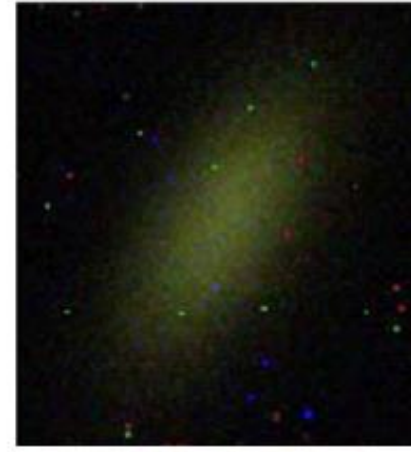
Abbreviation	Material	Activator	max. emission	decay time
Quartz	SiO <sub>2</sub>	none	optical	< 10 ns
	CsI	Tl	550 nm	1 $\mu$ s
	ZnS	Ag	450 nm	0.2 $\mu$ s
Chromolux	Al <sub>2</sub> O <sub>3</sub>	Cr	700 nm	100 ms
	Li glass	Ce	400 nm	0.1 $\mu$ s
P43	Gd <sub>2</sub> O <sub>2</sub> S	Tb	545 nm	1 ms
P46	Y <sub>3</sub> Al <sub>5</sub> O <sub>12</sub>	Ce	530 nm	0.3 $\mu$ s
P47	Y <sub>2</sub> Si <sub>5</sub> O <sub>5</sub>	Ce	400 nm	50 ns



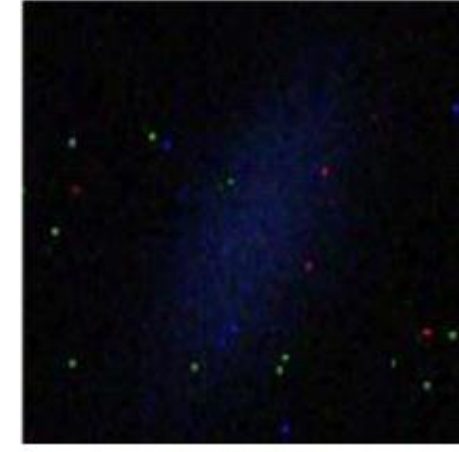
$\text{Al}_2\text{O}_3$



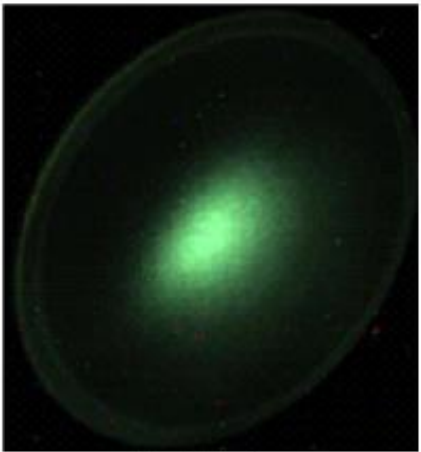
$\text{Al}_2\text{O}_3:\text{Cr}$



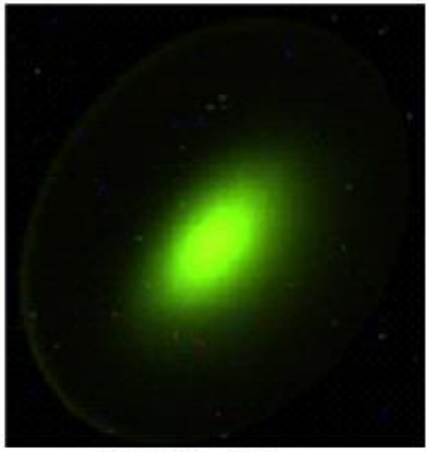
$\text{ZrO}_2:\text{Mg}$



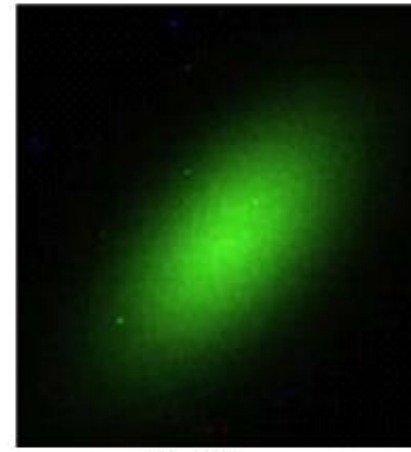
Herasil



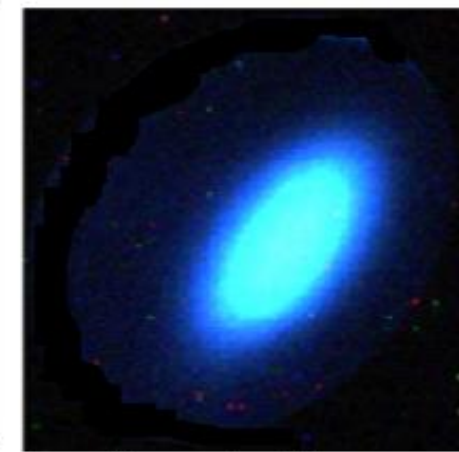
$\text{CsI}:\text{TI}$



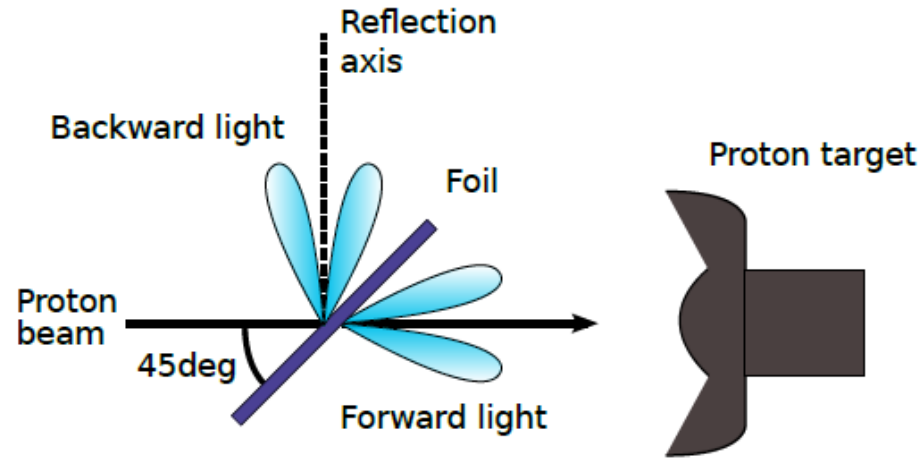
$\text{YAG}:\text{Ce}$



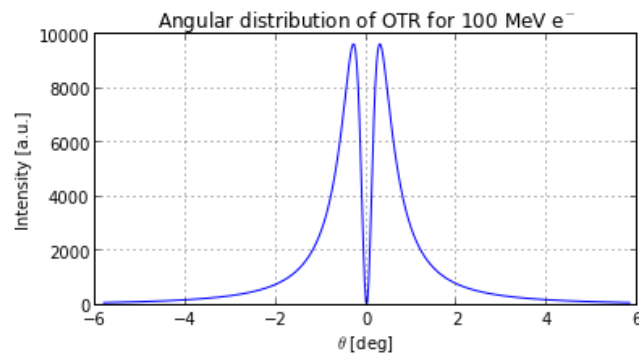
P43



$\text{Quartz}:\text{Ce}$

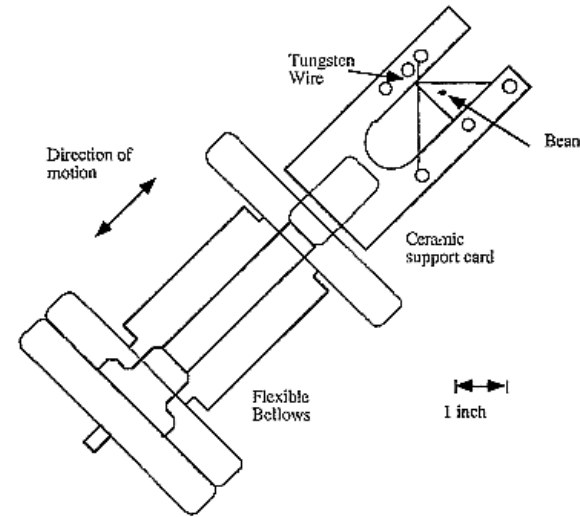
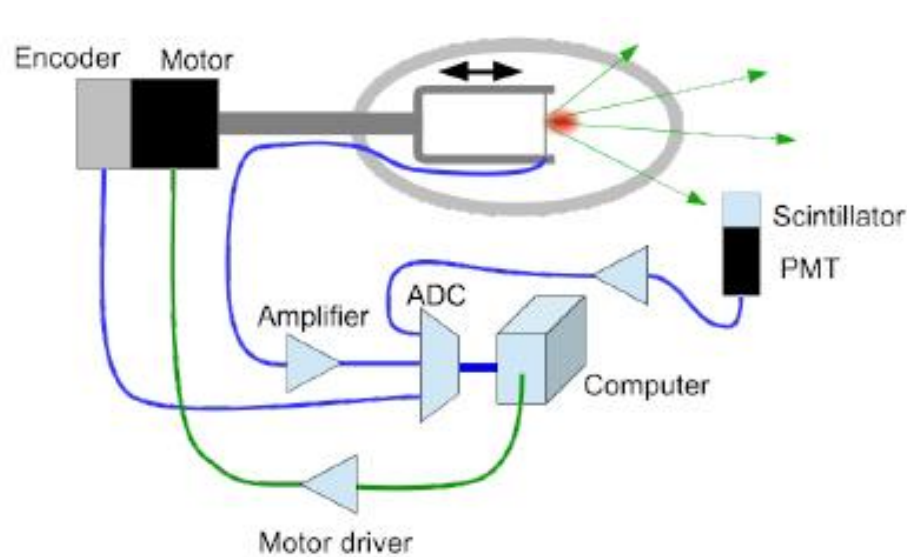


Credit: D. Morris, et al., TRIUMF

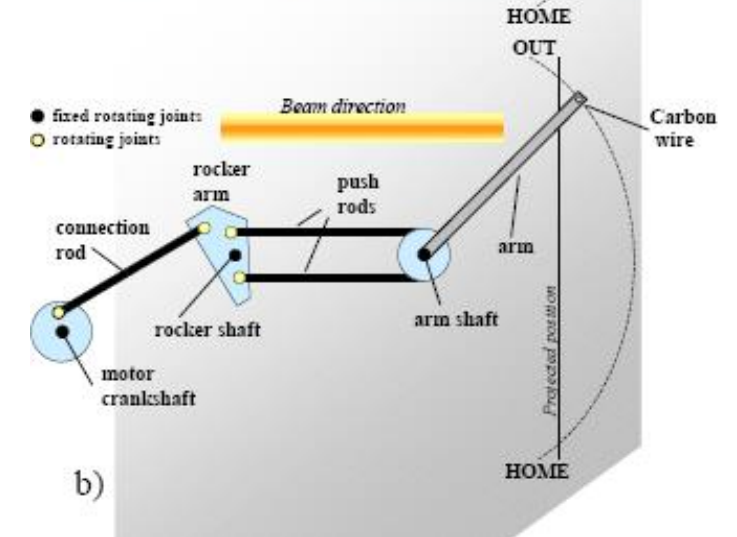


E. Bravin, Cern Accelerator School on Beam Instrumentation  
2-15 June 2018, Tuusula, Finland

- Radiation is emitted when a charged particle crosses the boundary of different dielectric properties
- Radiation has defined angular distribution
- Radiation is radially polarised



SLAC SLC high resolution 3 axis scanners



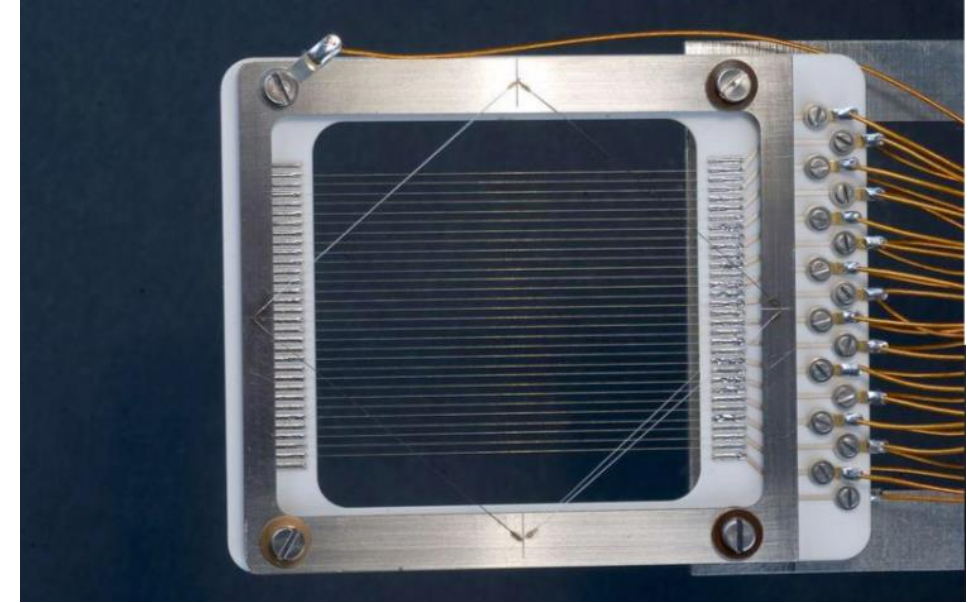
CERN "flying wires"

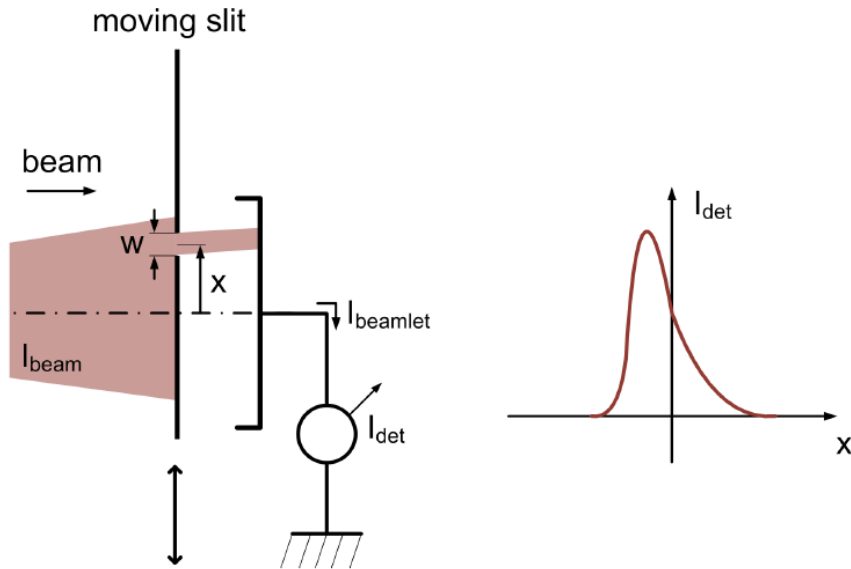
Scans a thin wire or a needle across the beam. Detects secondary emission current or high energy secondary particles (scintillator + PMT)

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- Similar to wire scanner
- The SE current from each wire or strip is acquired independently
- Wire spacing down to a few hundreds' microns
- Single shot measurement





- Similar to wire scanner
- Beam pass through a slit and then the intensity is measured by faraday cup or scintillator.
- Slit could be vertical or horizontal
- Useful for low energy and low intensity ( $I \gg I_{\text{SEM}}$ )

- Similar to wire scanner
- But deal with lower intensity
- Measured CDF instead of PDF

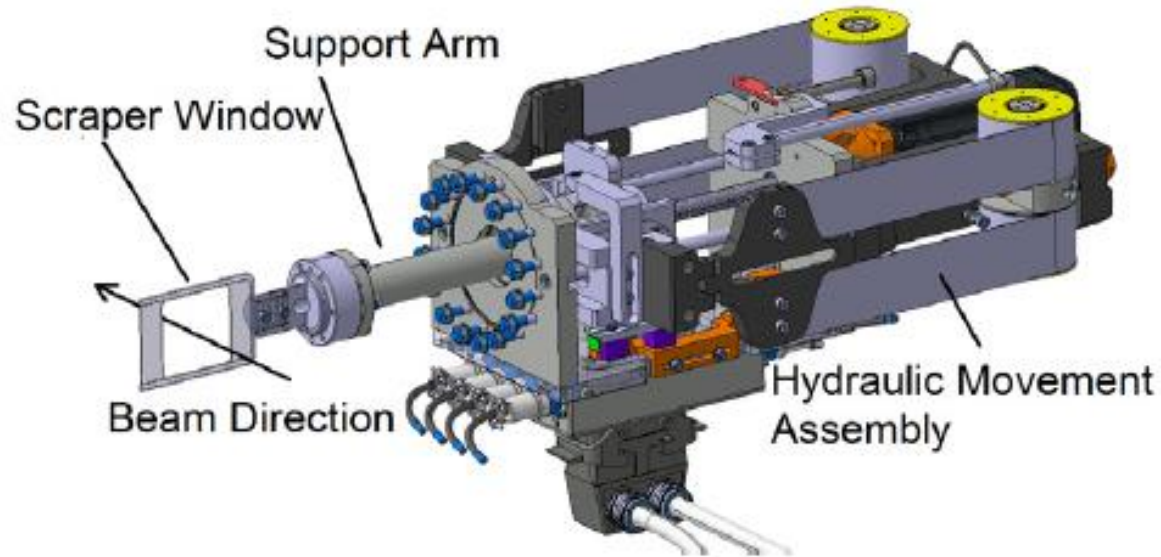
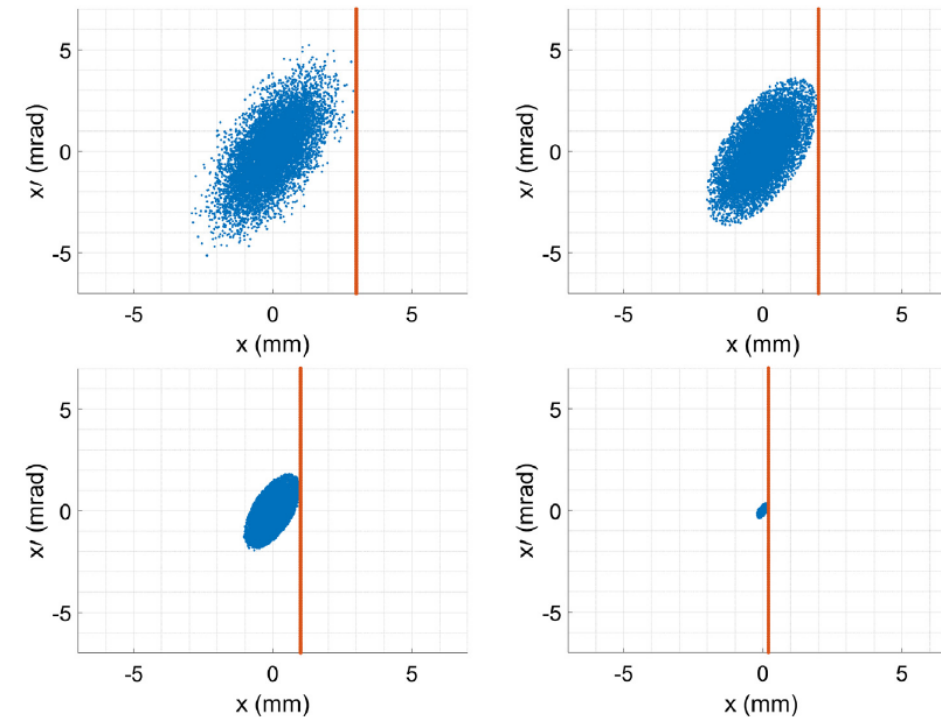
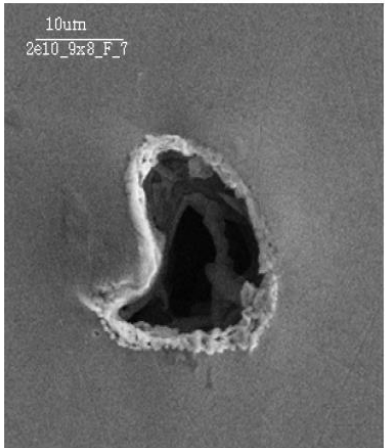


Fig. 4. A model of the horizontal scraper blade window in the extended position for use in ELENA [17].

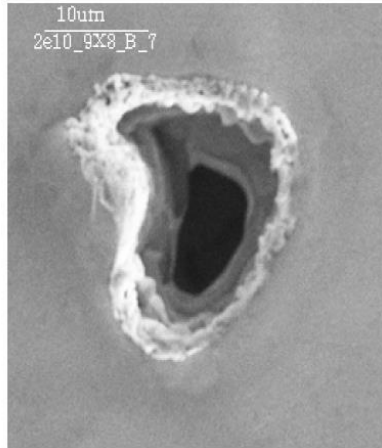


J. Hunts, et al., NIMA, Vol 896, Pages 139-151.

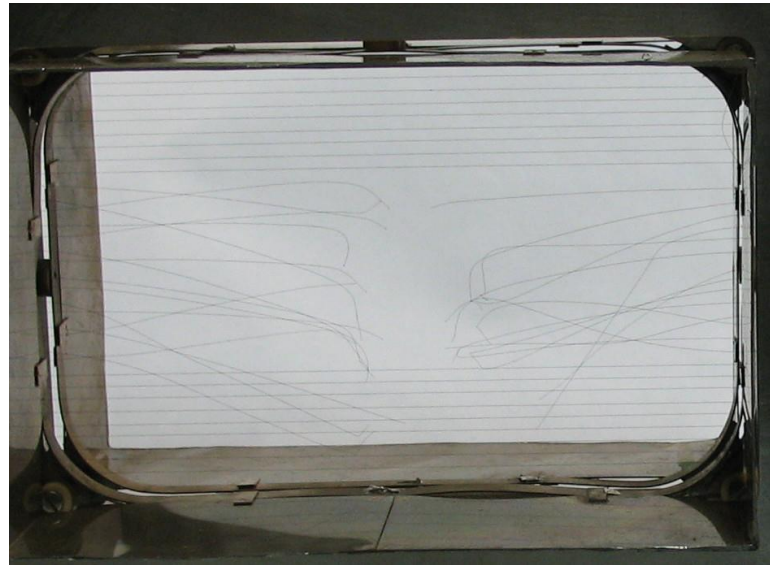
- Energy deposition
  - ▣ Signals are often proportional to the deposited energy
  - ▣ Energy deposition can cause damage to the instrument



Damaged screen



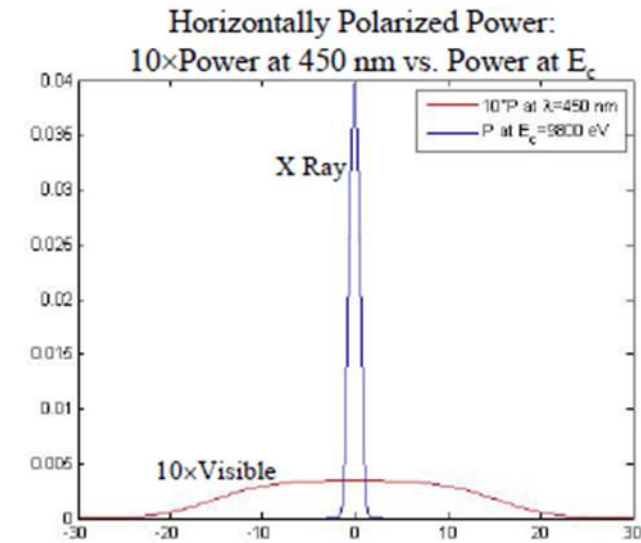
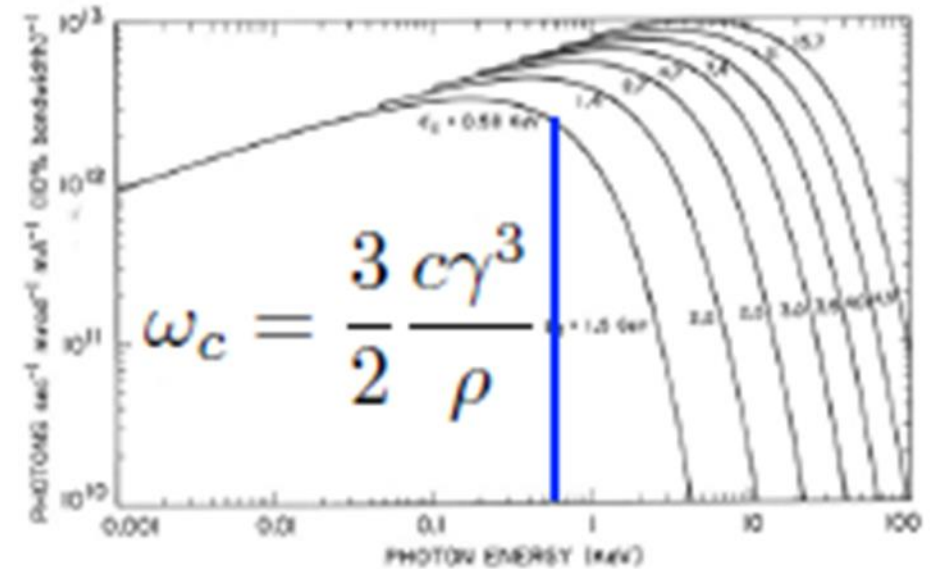
Damaged SEM Grid



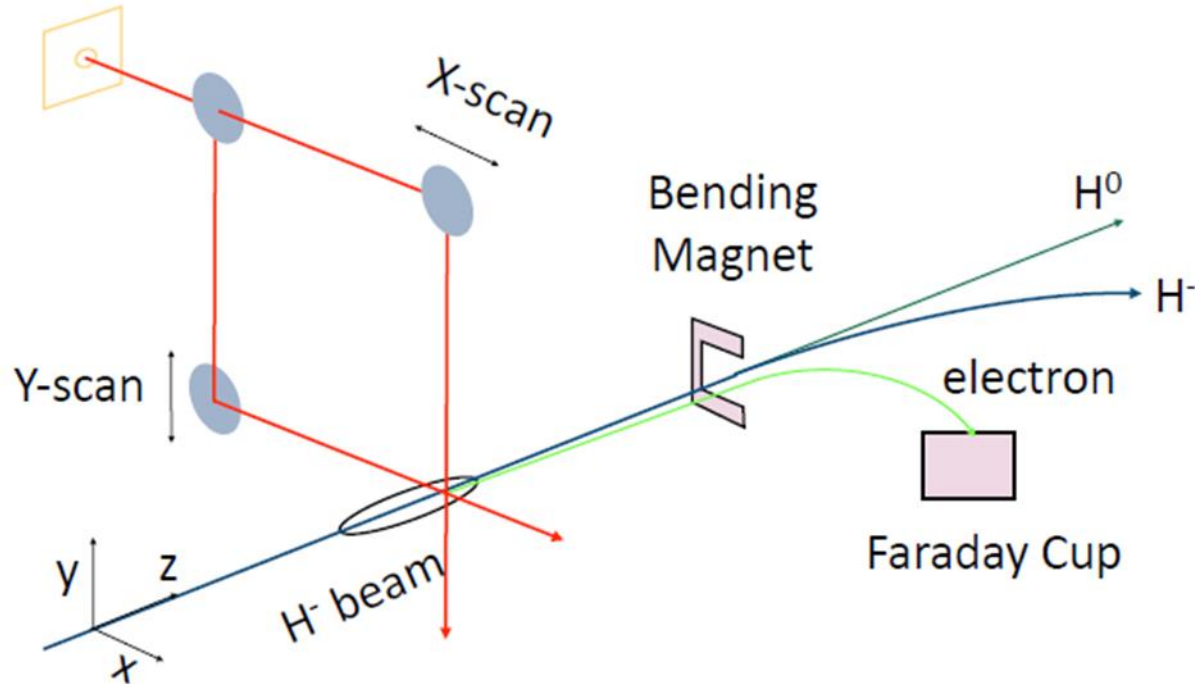
Damaged OTR screen

- Ideally: **Non-invasive.**

- Synchrotron radiation is broad band.
- Visible wavelength
  - ▣ Optical component is easy to implement.
  - ▣ diffraction limits the resolution at longer wavelengths when the beam is small
- X-ray
  - ▣ Better resolution
  - ▣ Hard to form an image
    - Pinhole camera
    - Zone plates



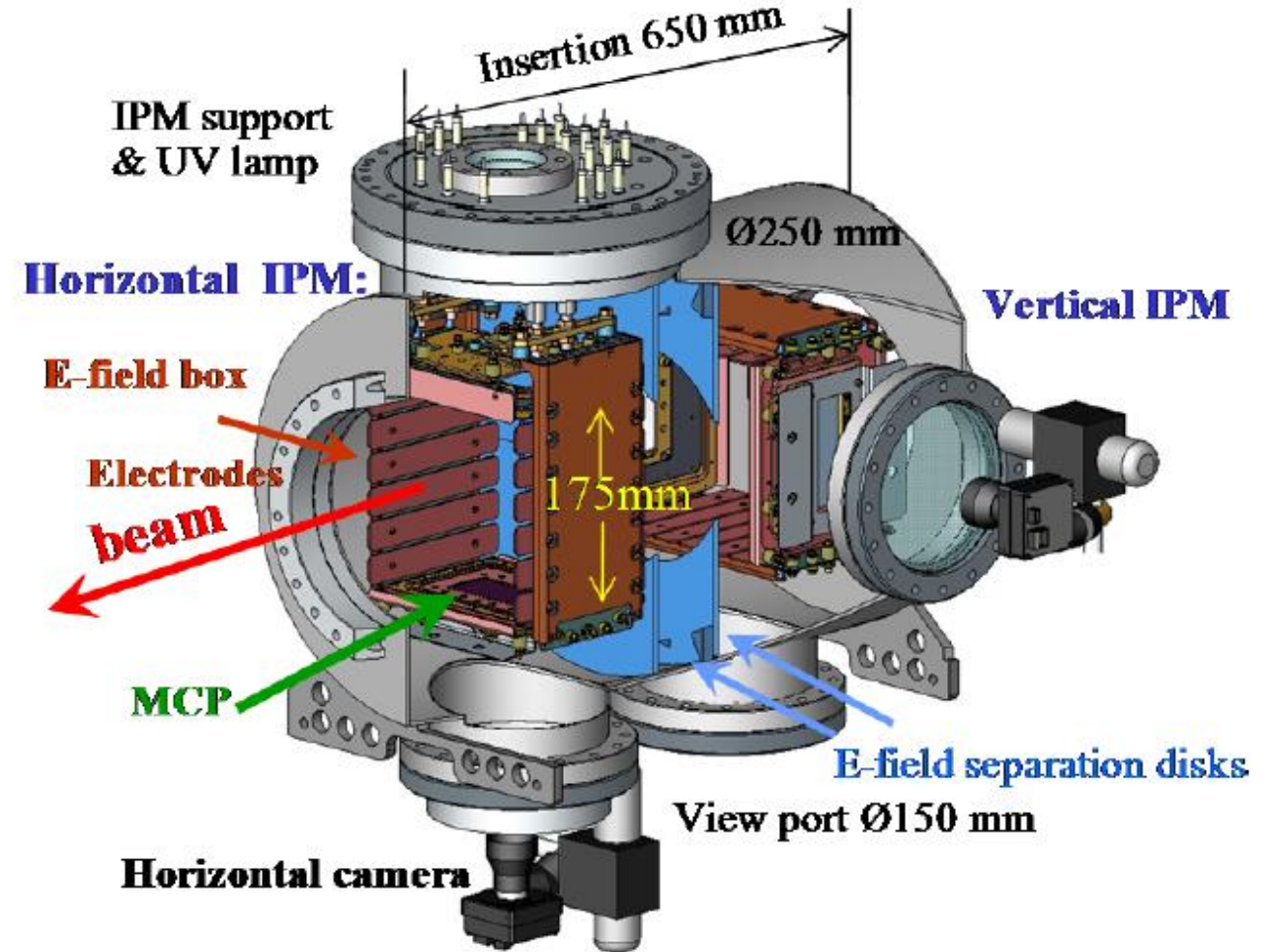
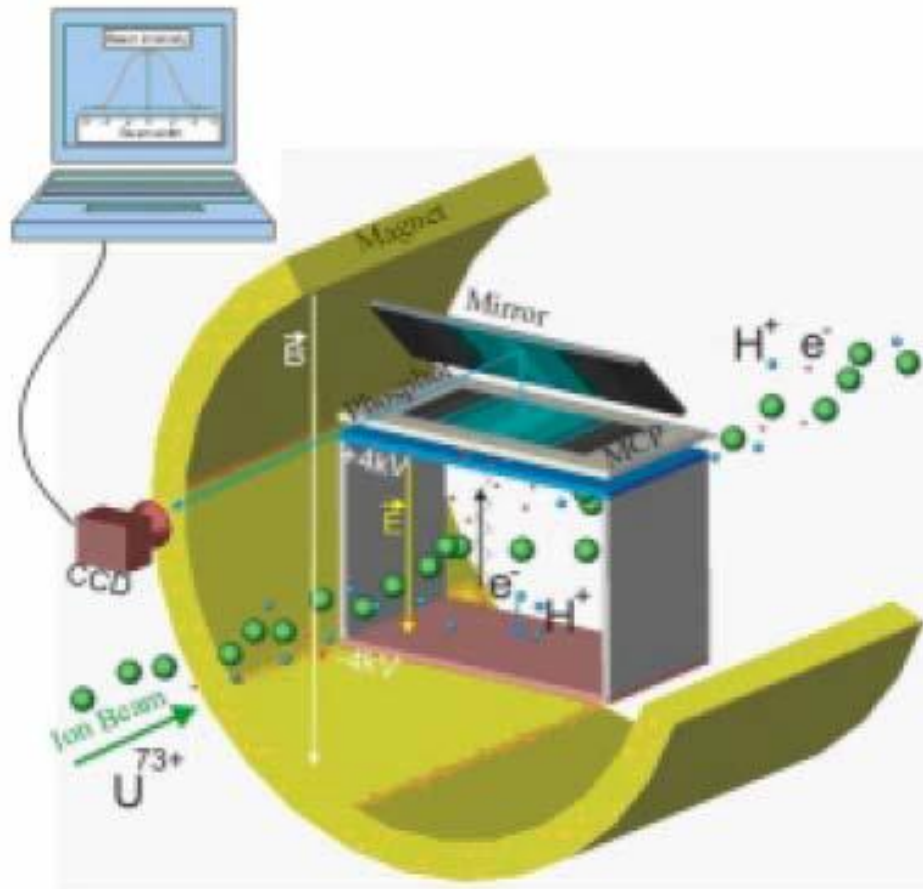




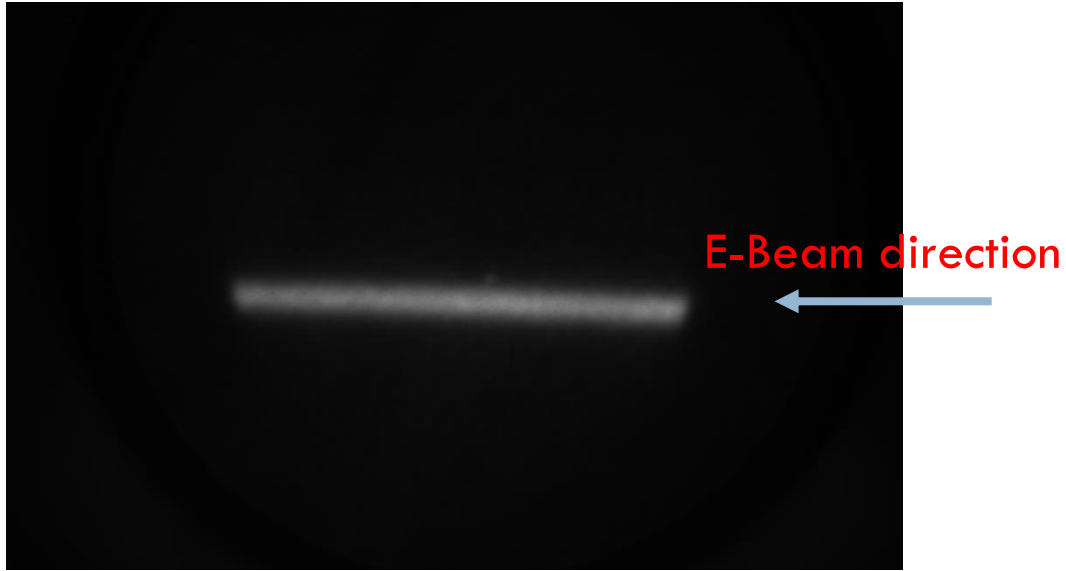
- First ionization potential for H<sup>-</sup> ions is 0.75eV.
- Photons with  $\lambda < 1500\text{nm}$  can separate H<sup>-</sup> ion into free electron and neutral H.
- The H<sup>-</sup> ion has no excited states so the electron is removed into the continuum.
- **Laser can be used to mark a portion of beam by neutralization.**
- Once a portion of the beam is marked, measurements can be made on the neutral beam, the removed electrons, or the reduced beam current with beam current transformer or BPM stripline.

T. Shea, Laser Diagnostics for H<sup>-</sup> beams, , Accelerator Beam diagnostics, USPAS 2009



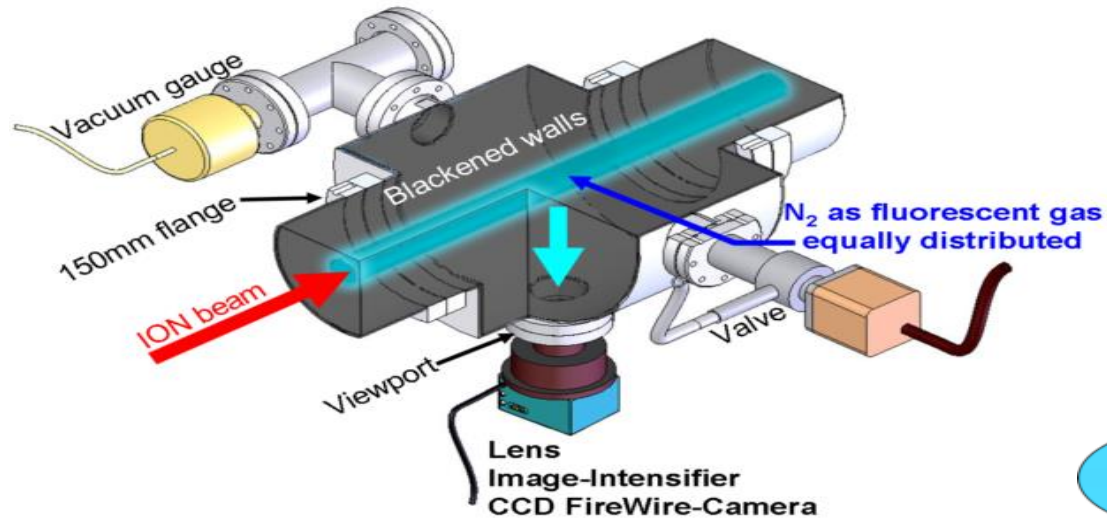


Credit: P. Fork, GSI



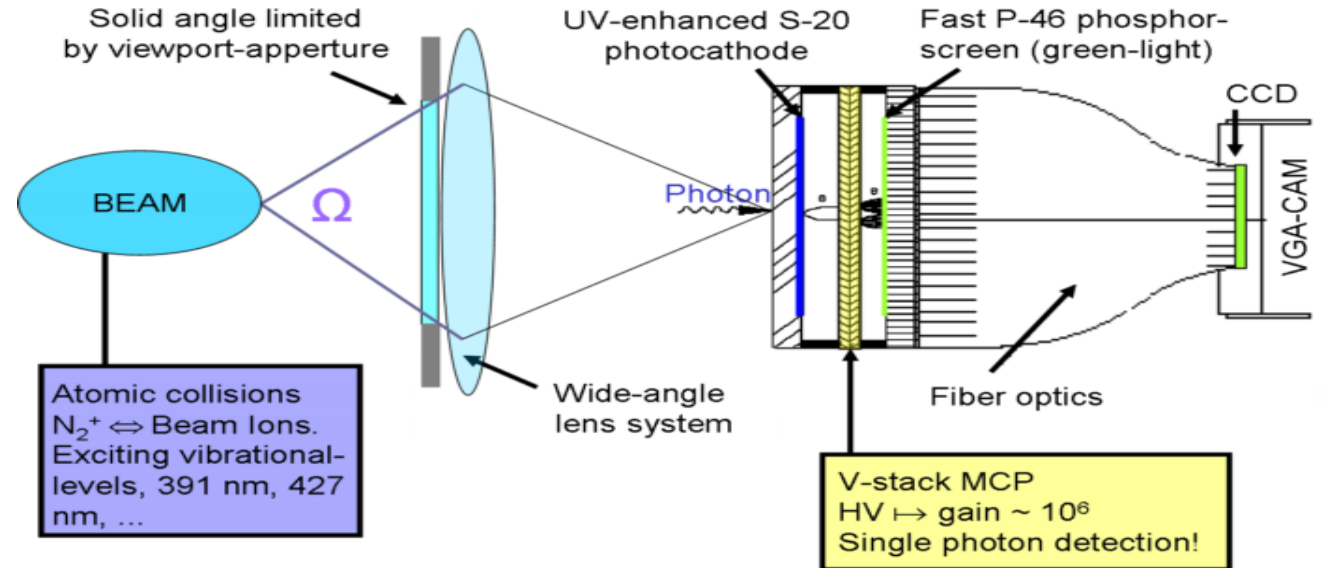
Give you a one-dimensional profile!

- Secondary ions or electrons are collected.
- Magnetic field are used to compensate the profile distortion by self space charge force or wake fields.
- Secondary particles are collected by electronics or optical (scintillator plus MCP)



**BIF detection principle** - How the beam induced fluorescence light is imaged, intensified and detected.\*

Schematic drawing of the BIF-monitor as installed at GSI UNILAC. \*



\*Credit: GSI, <http://www-bd.gsi.de/dokuwiki/doku.php>

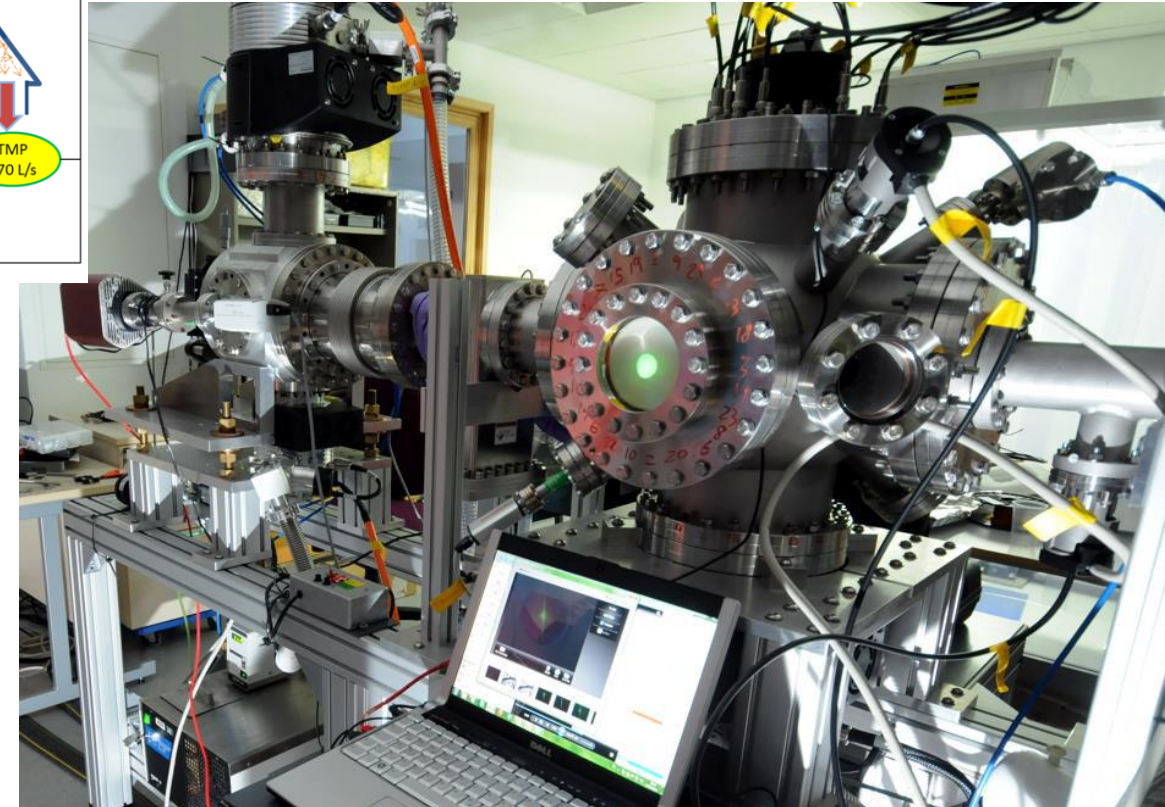
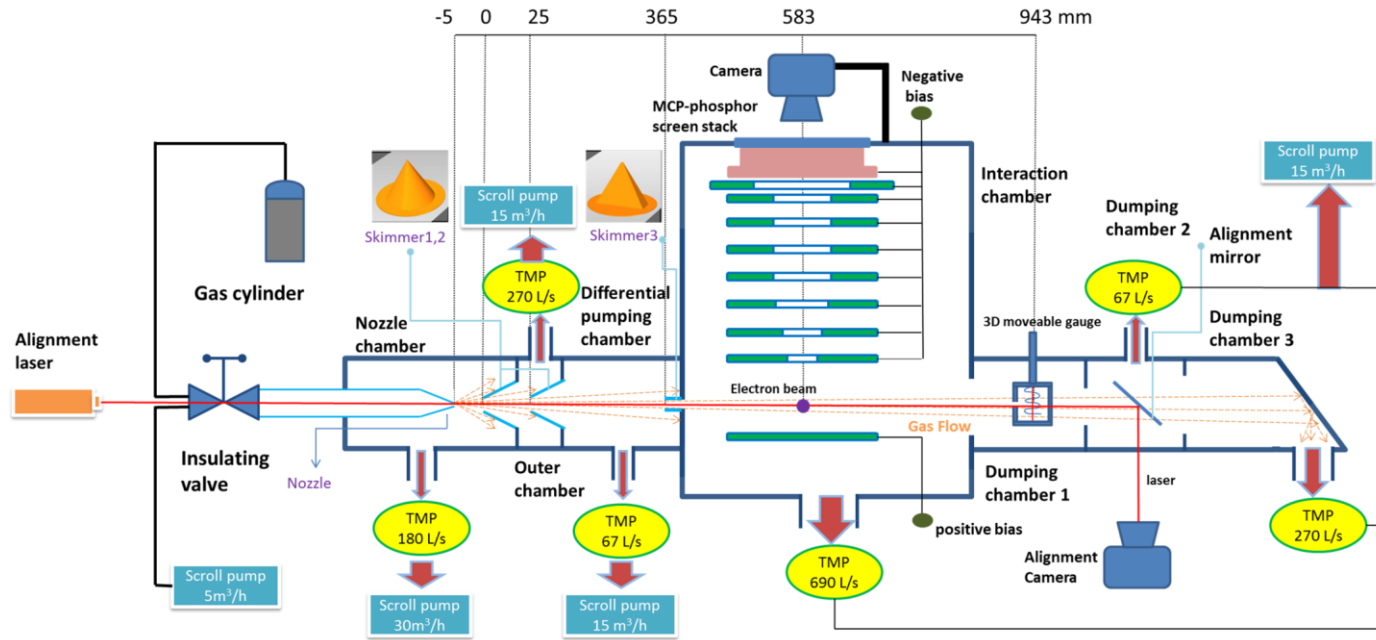
- The cross section for impact ionization and fluorescence dependent on the beam energy, residual gas species, and certain fluorescent wavelength.
- BIF has longer integration time due to lower cross section and viewed at certain solid angle.
- Might need gas injection using a leaking valve to increase the local pressure.
- Normally  $N_2$  has higher cross section, other gases such as Ne, Ar has been used.



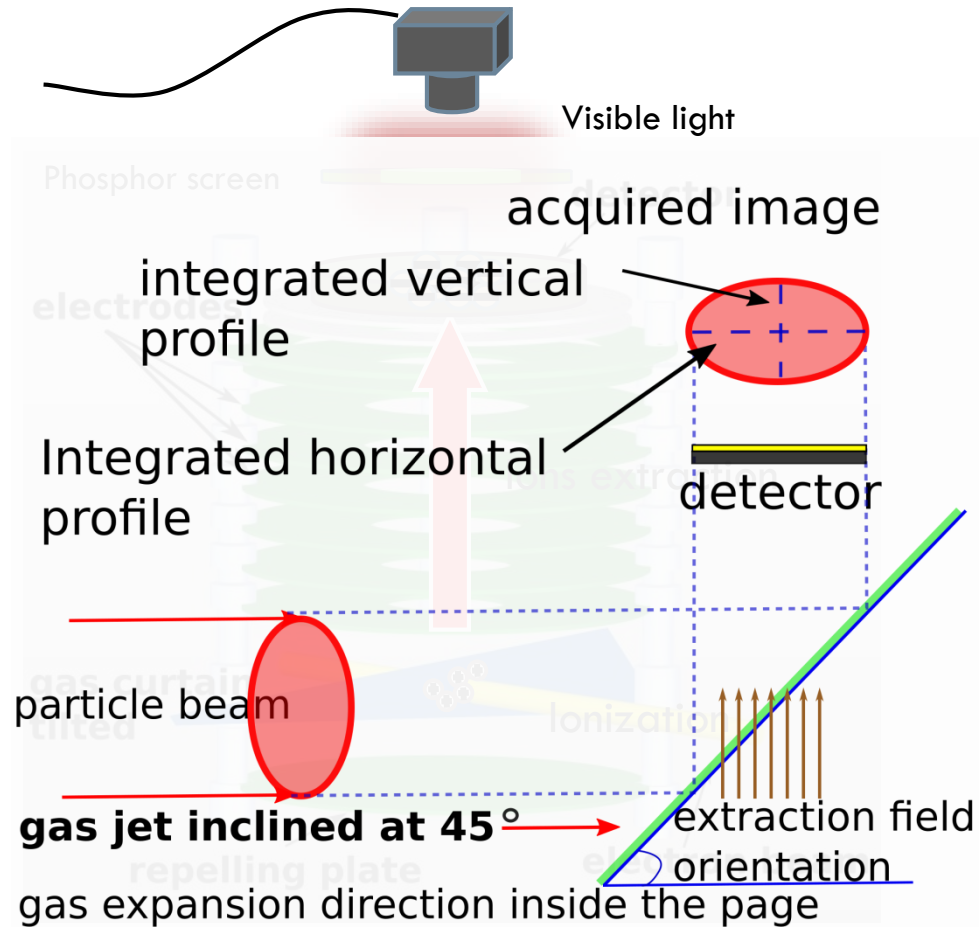
**Using Supersonic gas jet !**

- Low temperature
- High directional jet
- Non-invasive or minimum-invasive
- Not dependent on beam species, energy and intensity
- No damage threshold
- Not affect the vacuum very much





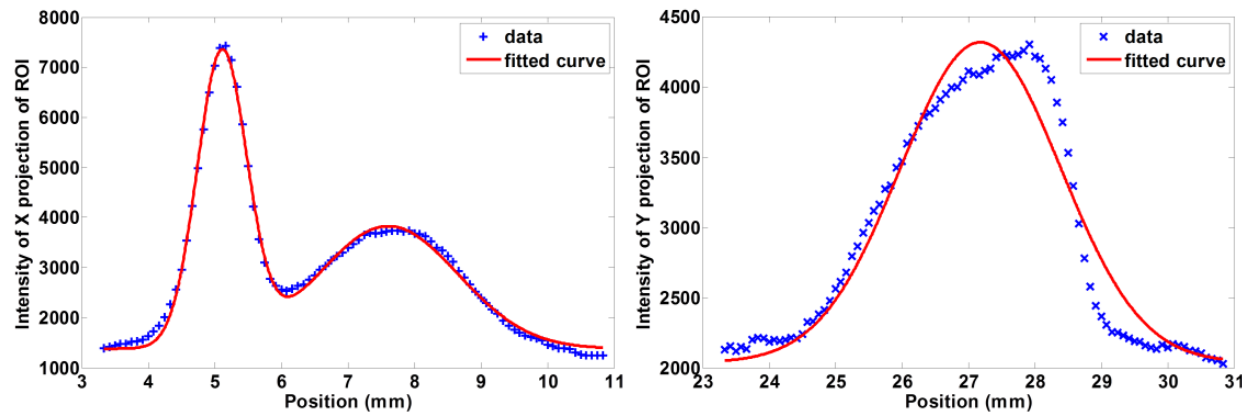
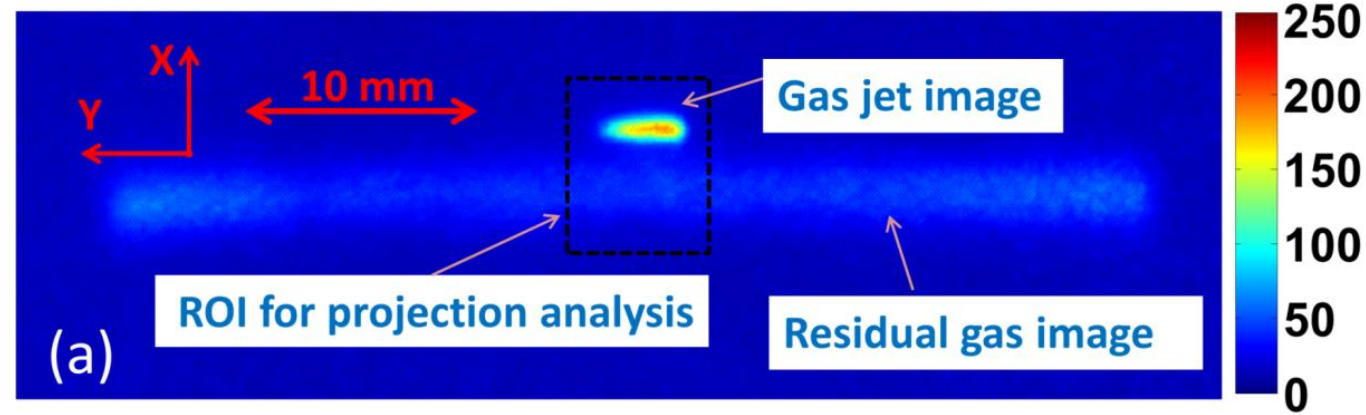




## Estimated jet property

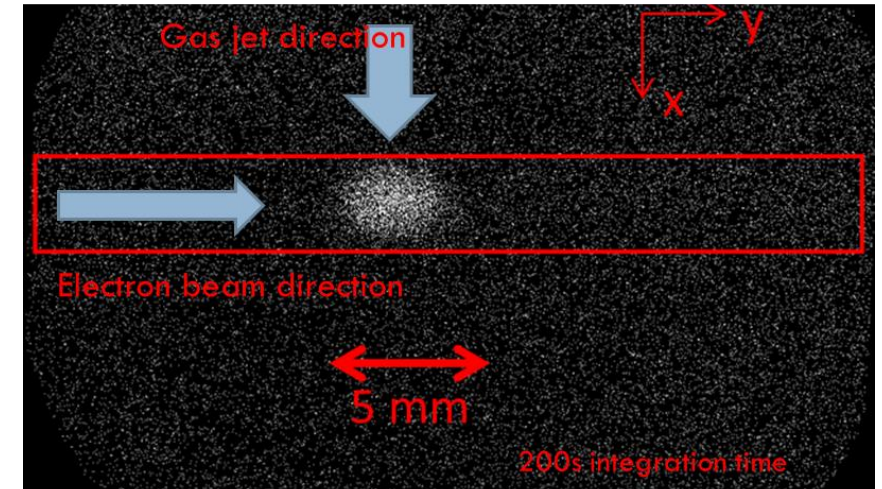
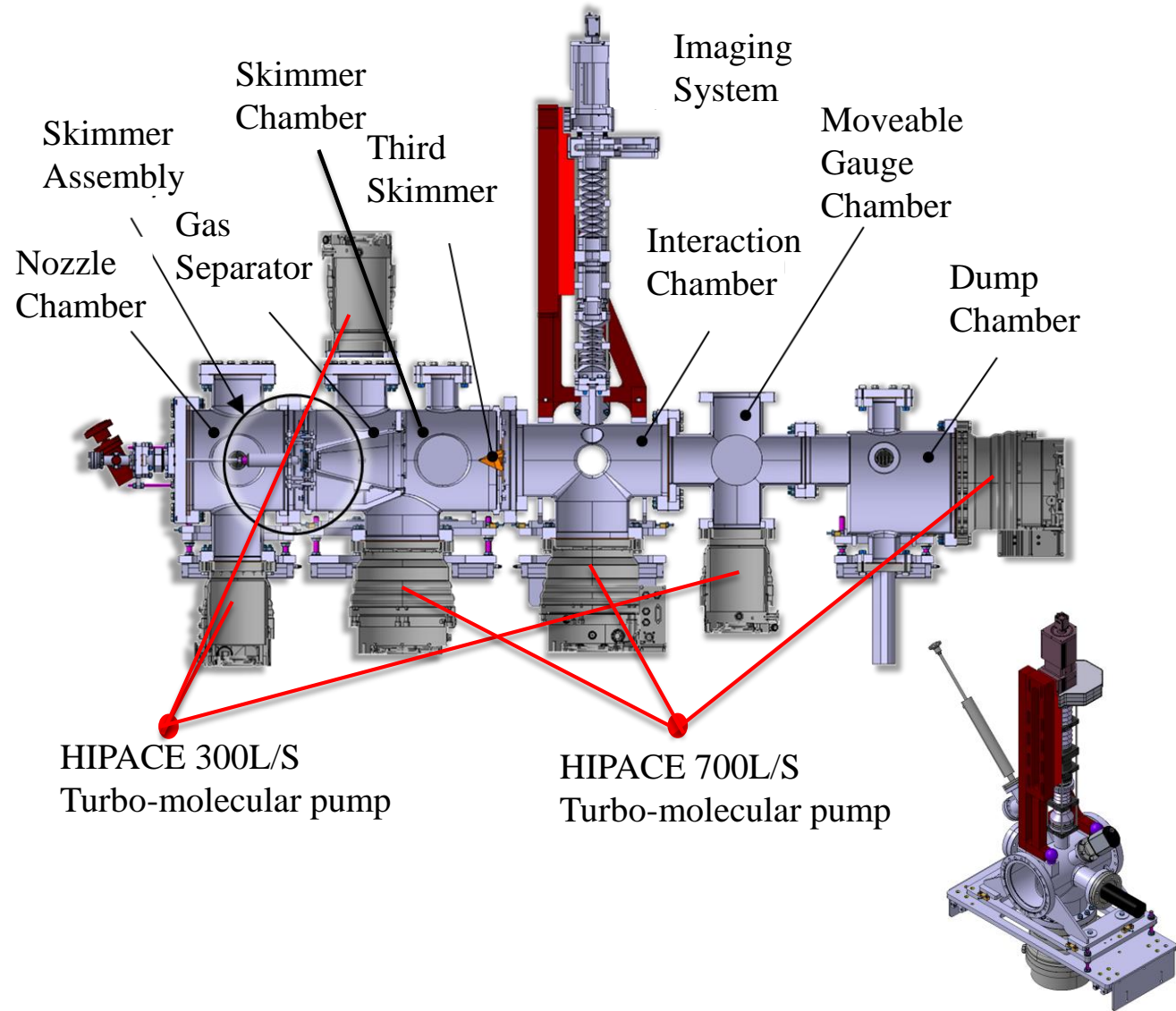
Parameter	Value
Density	$2.5 \times 10^{16}$ particle/m <sup>3</sup>
Thickness	0.5 mm
Vertical size	5 mm

Estimated integration time = 1 ms



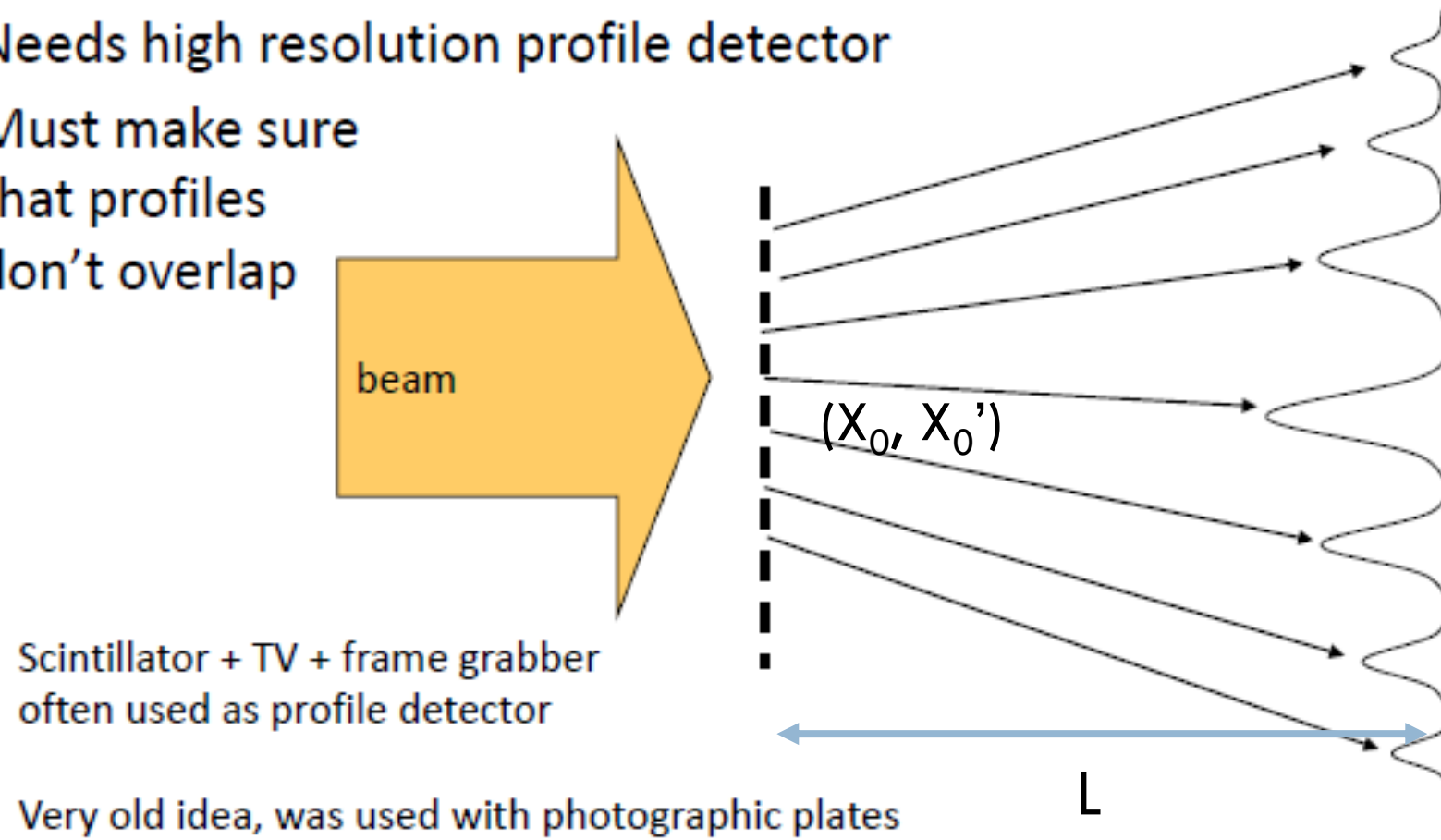
Setting	Value
Energy	3.75 keV
Current	$\sim 5.0 \mu\text{A}$
External field	7.5 kV/m
Exposure	70 ms

size	Value
Xrms	0.42
Yrms	1.23
Xrms from residual	1.01



# Emittance measurement

- Needs high resolution profile detector
- Must make sure that profiles don't overlap

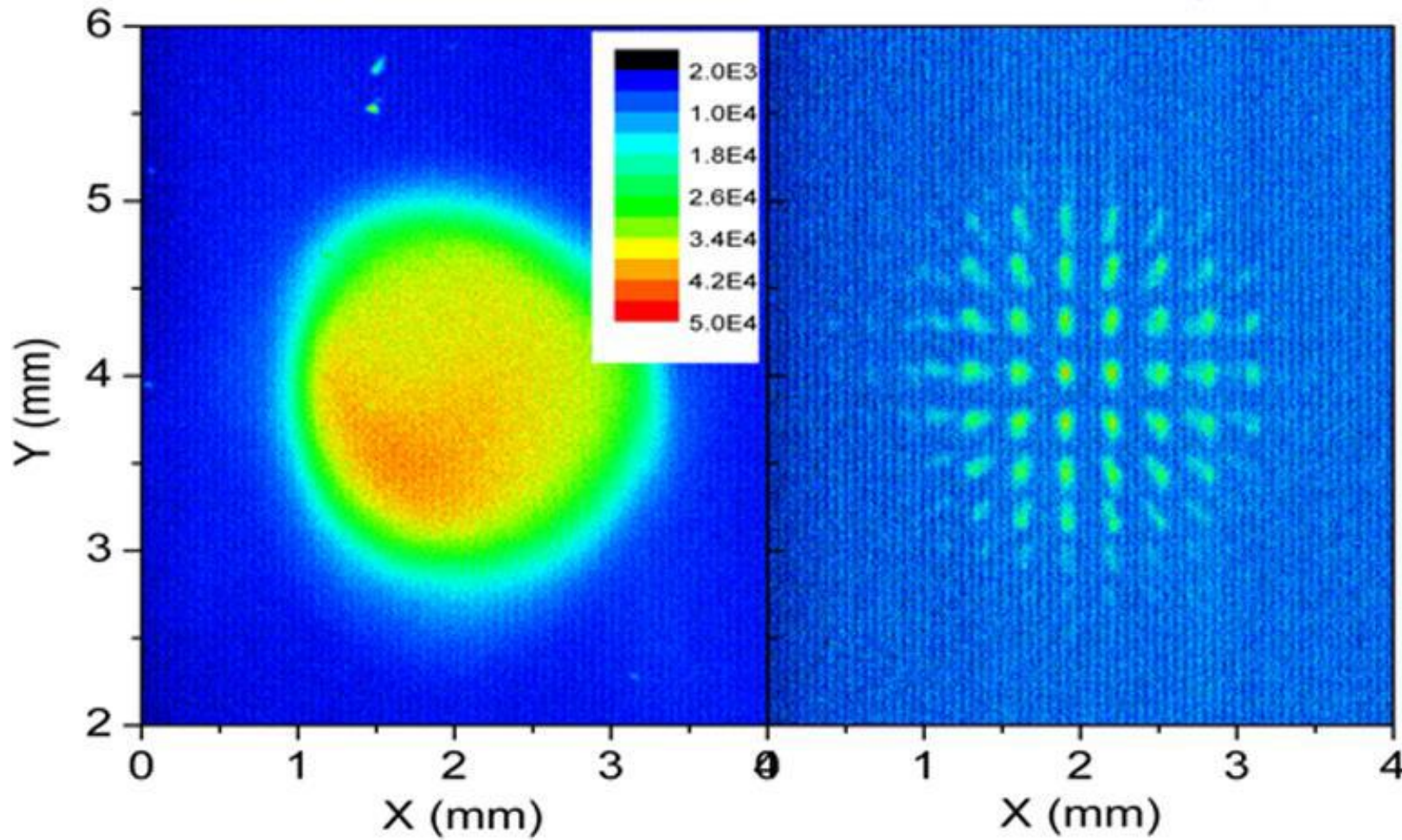


$$X'_0 = \frac{2\sigma - d}{L}$$

Slit size =  $d$

Beamlet rms size =  $\sigma$



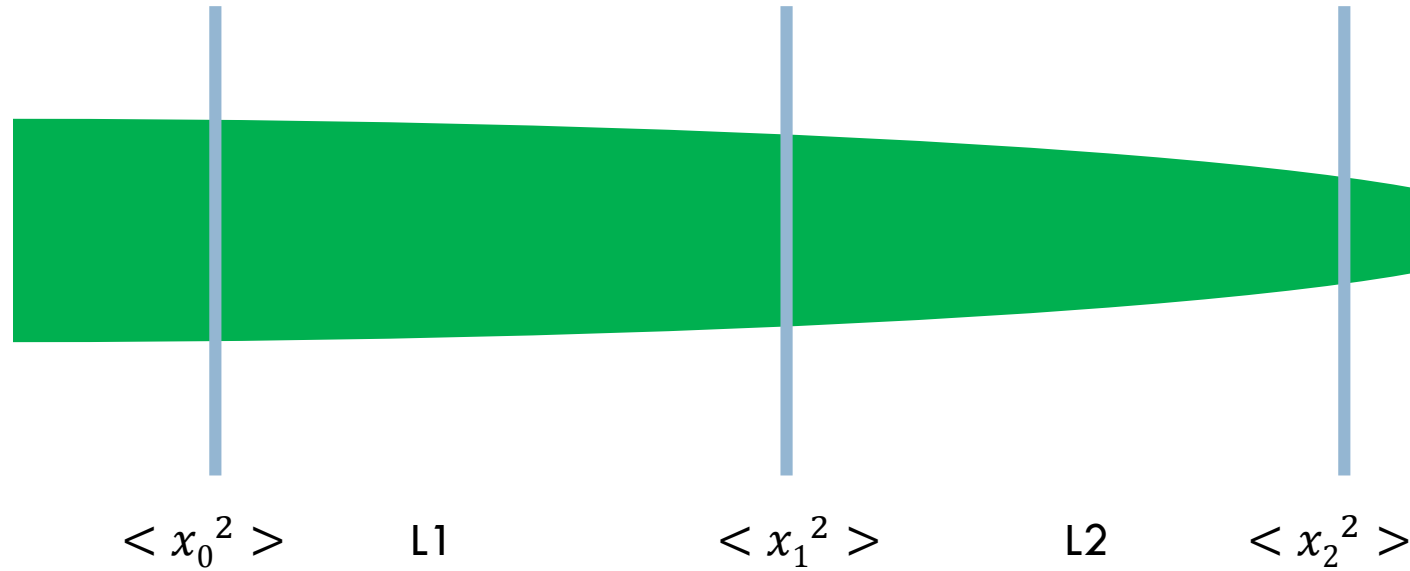


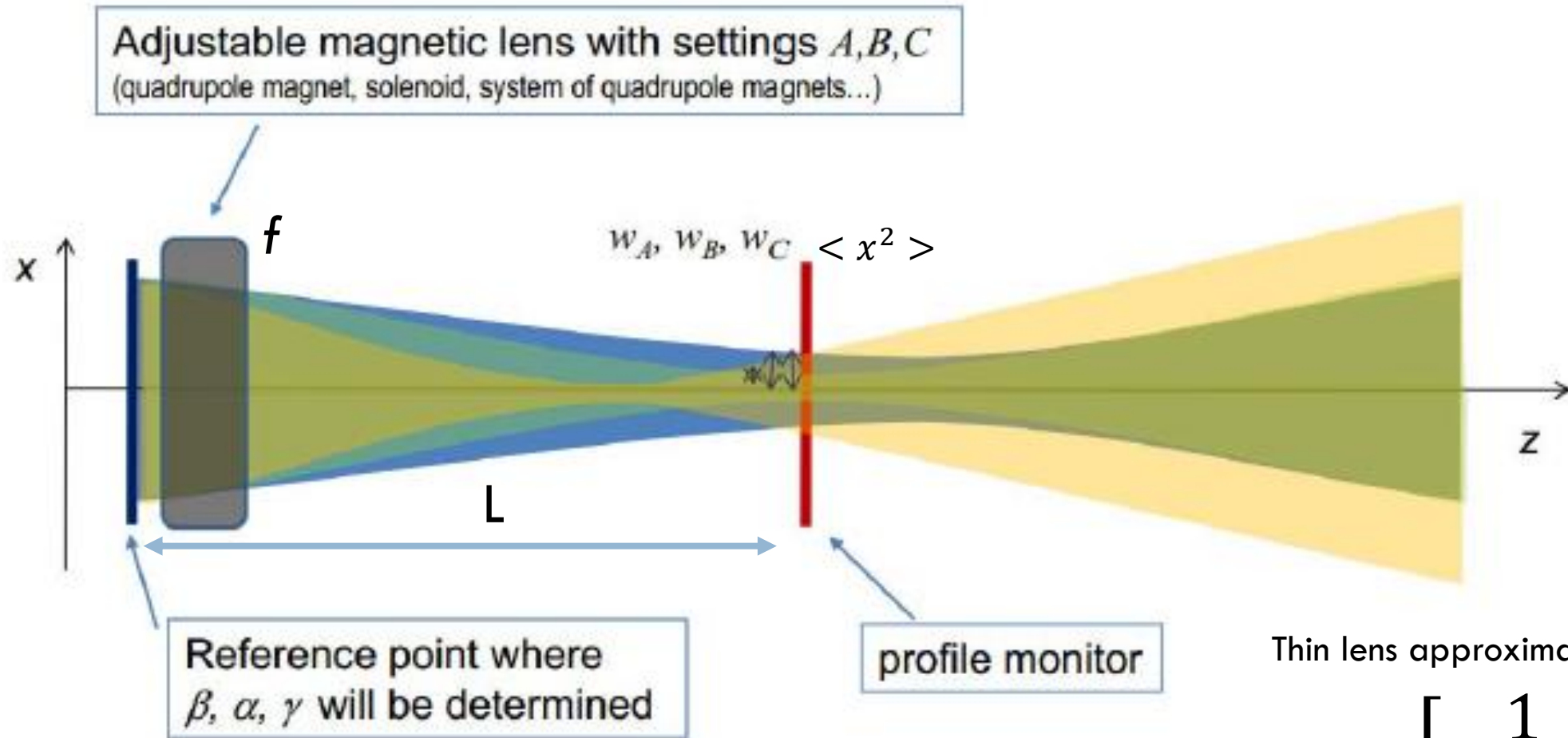


## □ Transfer matrix

$$\begin{bmatrix} 1 & L \\ 0 & 1 \end{bmatrix}$$

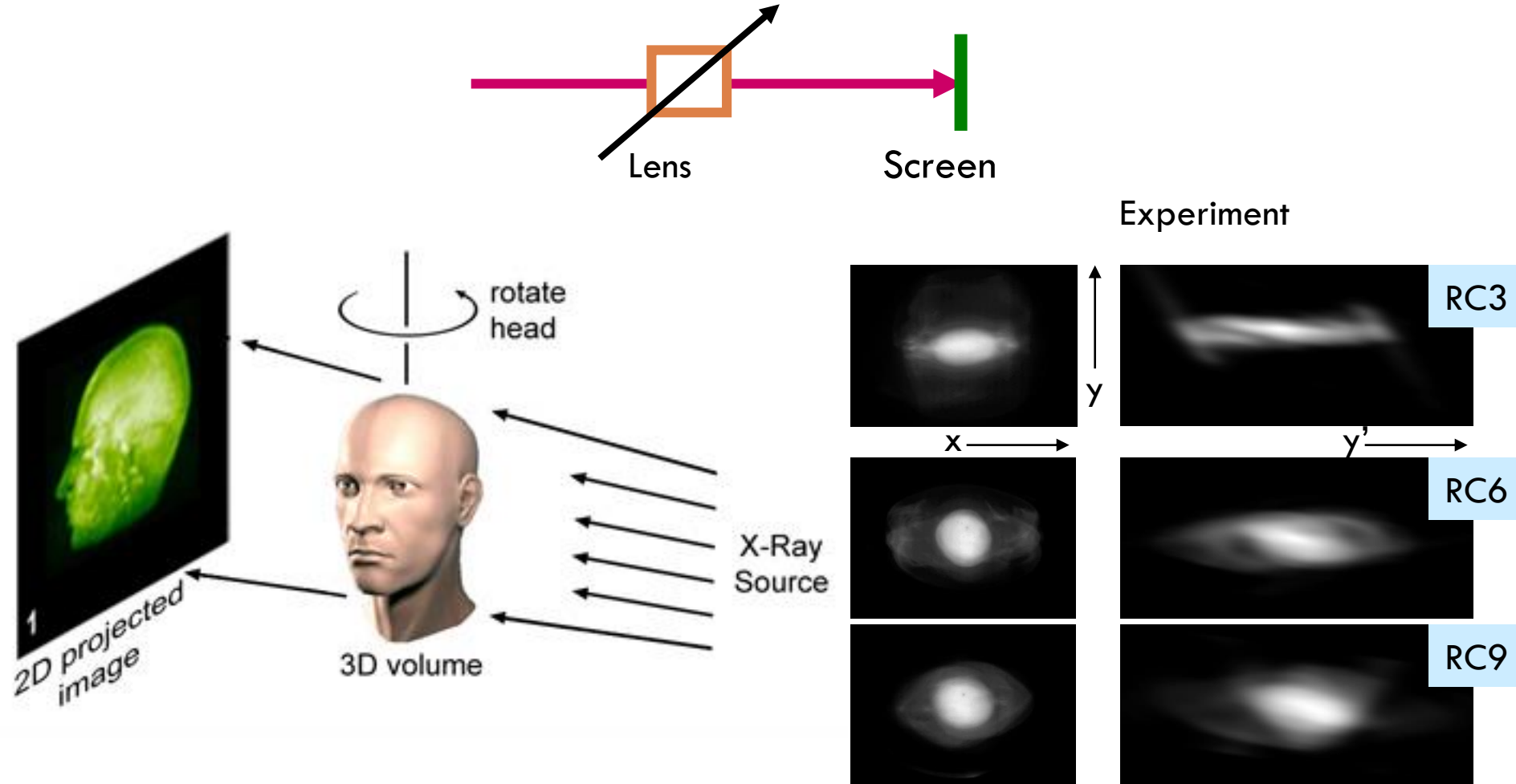
$$\begin{aligned} \langle x_1^2 \rangle &= \langle (x_0 + L_1 x'_0)^2 \rangle = \langle x_0^2 + 2L_1 x_0 x'_0 + x_0'^2 \rangle \\ &= \langle x_0^2 \rangle + 2L_1 \langle x_0 x'_0 \rangle + \langle x_0'^2 \rangle \end{aligned}$$





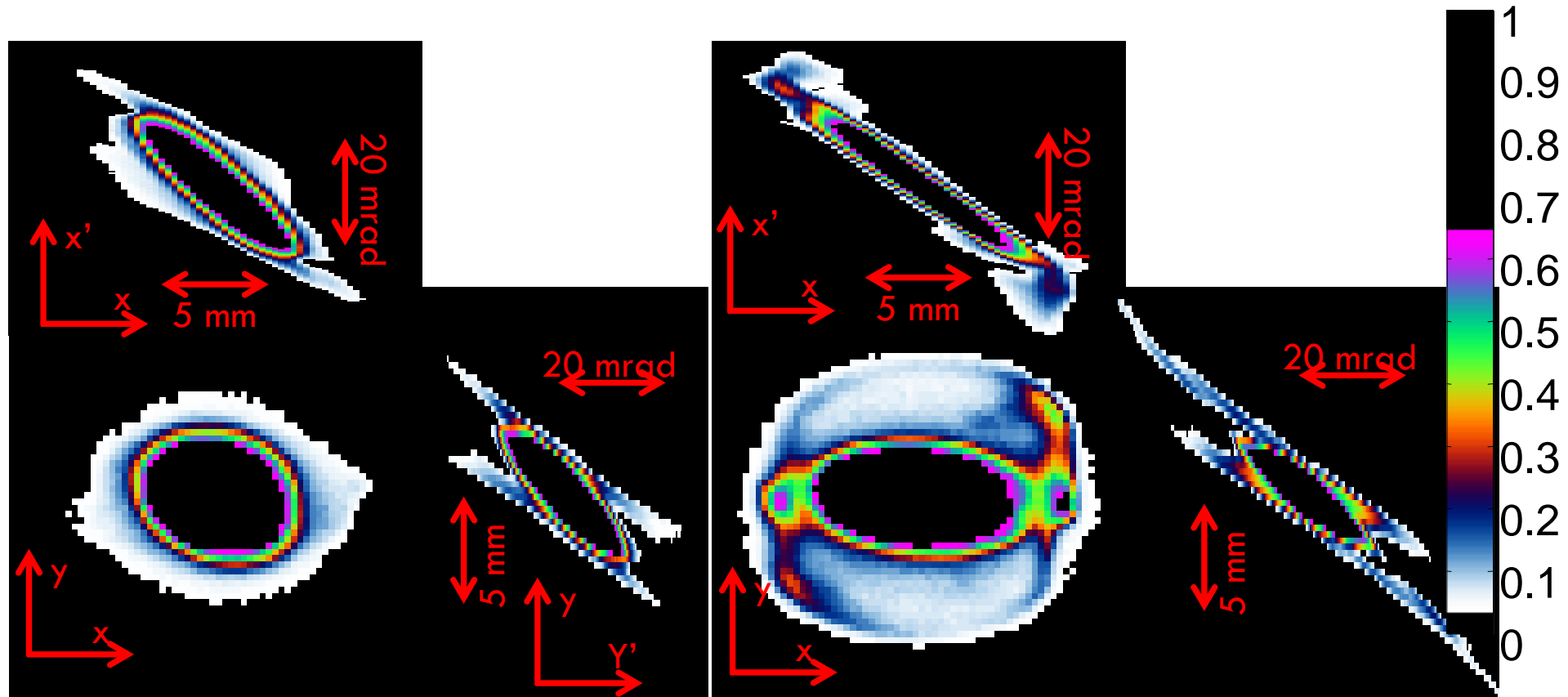
Thin lens approximation

$$\begin{bmatrix} 1 & 0 \\ -1/f & 1 \end{bmatrix}$$



Projected / Slice, using Quadrupoles / Solenoids  
with Space Charge

*D. Stratakis, R.A. Kishek, S. Bernal, et al., Physics of Plasmas 17, 056701 (2010).*

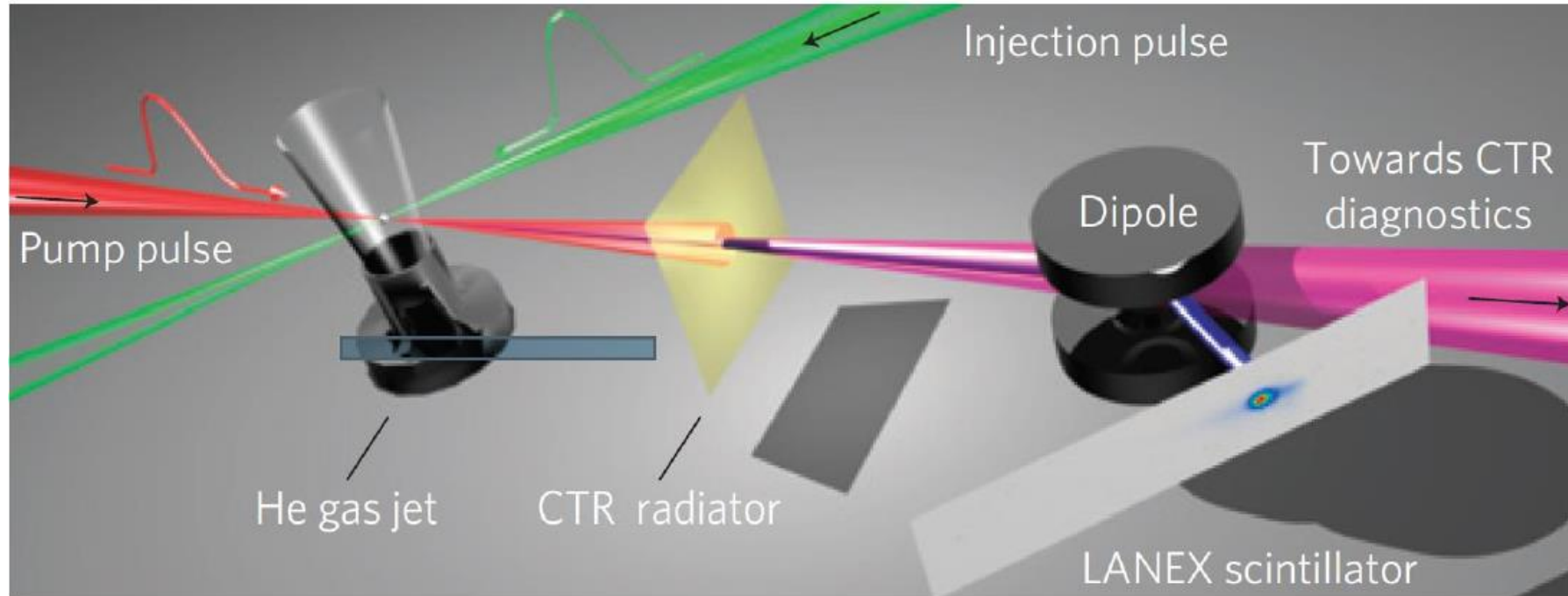


*H. Zhang, PhD thesis, university of Maryland, 2014*

Technique	Pros	Cons
Basic Optics	Simple to implement. Linear space charge OK. Small or large beams.	RMS emittance only. No phase-space.
Pepper-pot	Simple to implement. Space charge OK. No beam optics.	Coarse phase-space. Impractical for small beams.
Quad Scan	Different schemes. Easy computation.	Space charge limits. No phase-space. Linear optics assumed.
Slit-Wire	Phase space info. Integrated or t-resolved. Space charge OK.	S/N problems. Hard to implement. Comp. intensive.
Tomography	Detailed phase space info. Linear optics/sp. charge.	More beam manipulation required. Computationally intensive.

# Beam energy Monitoring

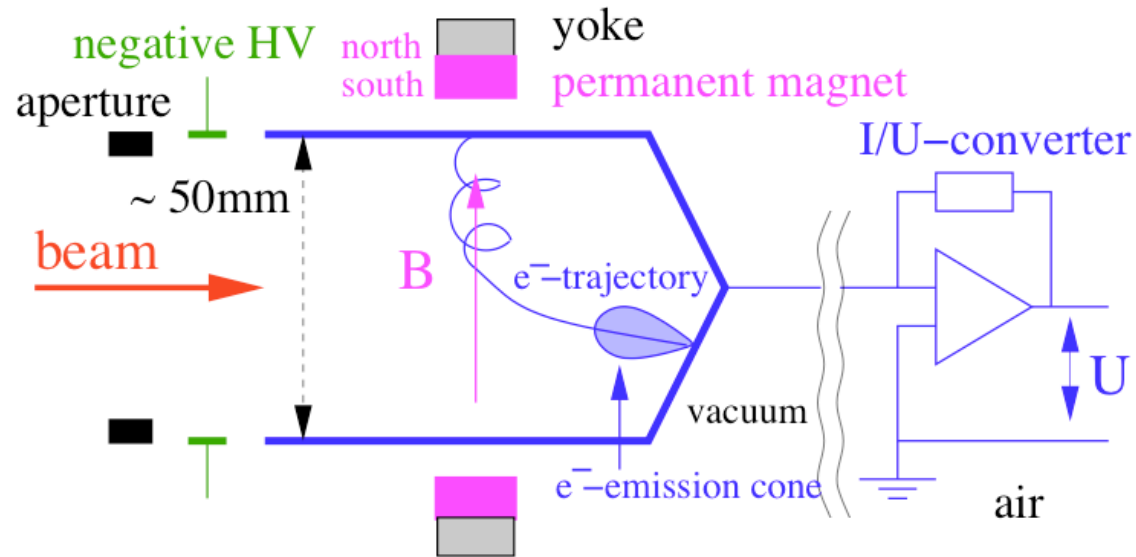




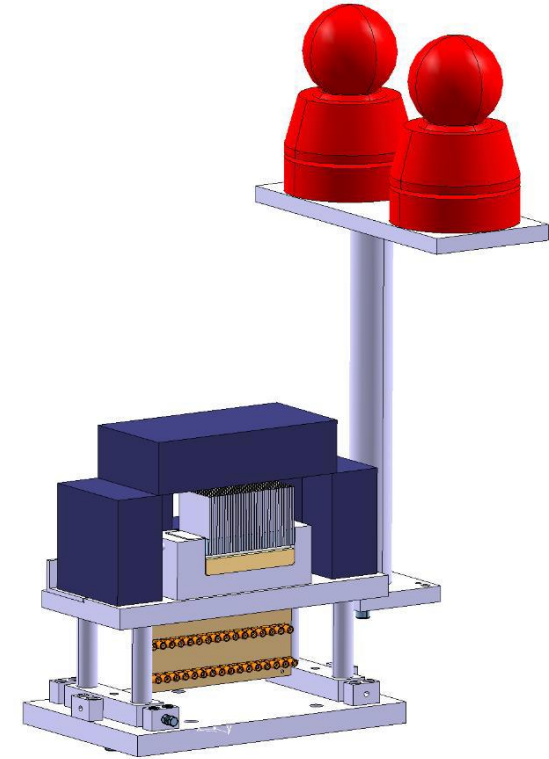
- 30 fs (FWHM) pump pulse and injection pulse collide at  $135^\circ$
- 3 mm He gas jet target, beam diameter @ foil:  $90\ \mu\text{m}$
- $100\ \mu\text{m}$  Al foil generates radiation after 15 mm
- Peak charge: 15 pC and peak energy: 84 MeV

O. Lundh, et al., Nature Physics (2011).

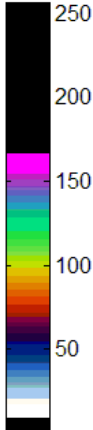
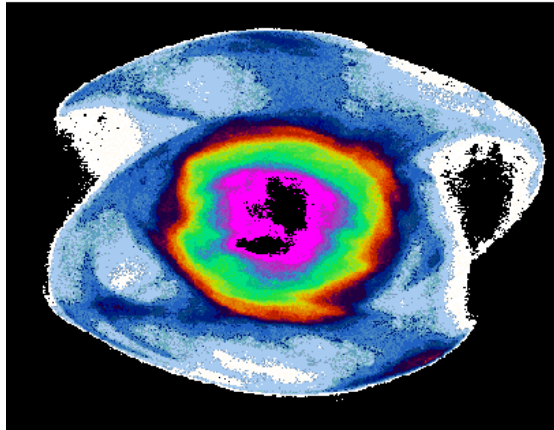
## Faraday cup



## Segmented Dump



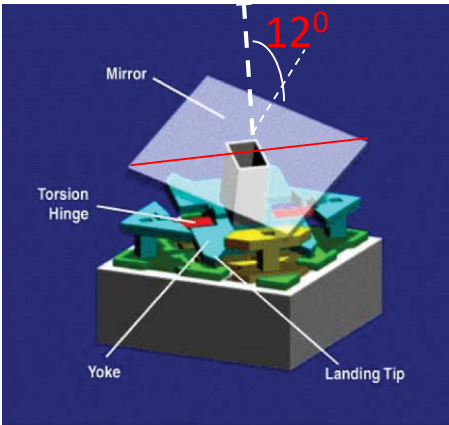
# Beam halo Monitoring



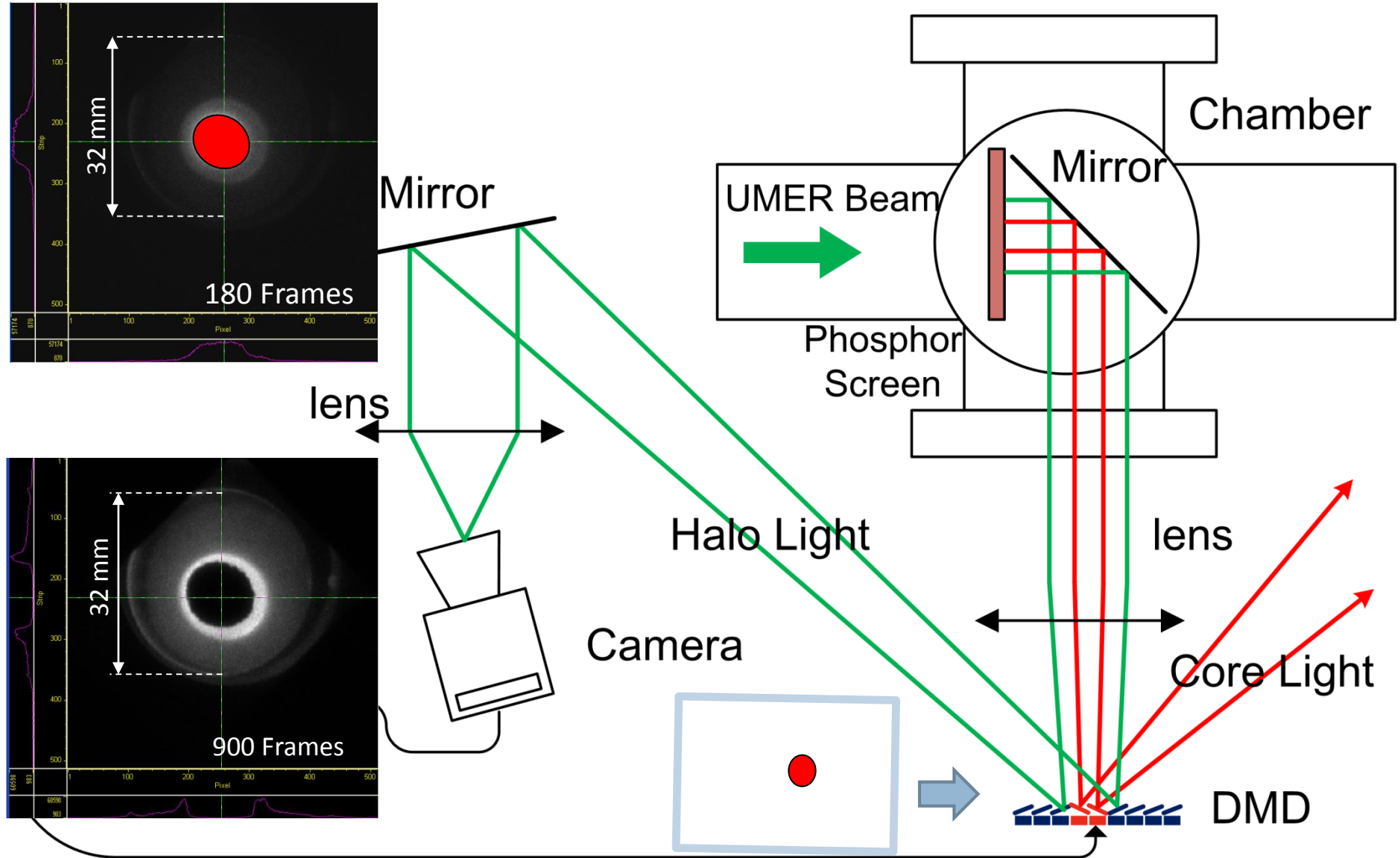
## Causes of Beam Halo

- Nonlinear forces due to space charge
- Parametric resonances
- Scattered Laser Light in Photo-cathodes:
- Misalignment, Magnet error, noise

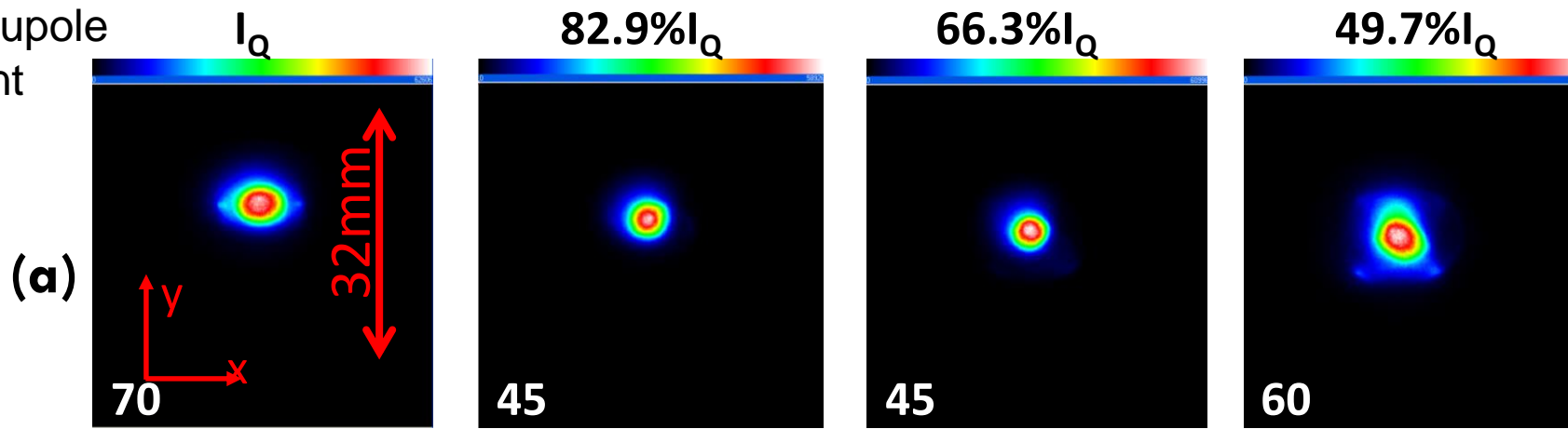
- Beam Halo has many negative effects
  - Nuclear Activation of The Transport Channel
  - Emittance Growth
  - Emission of Secondary Electrons
  - Increasing Noise in The Detectors



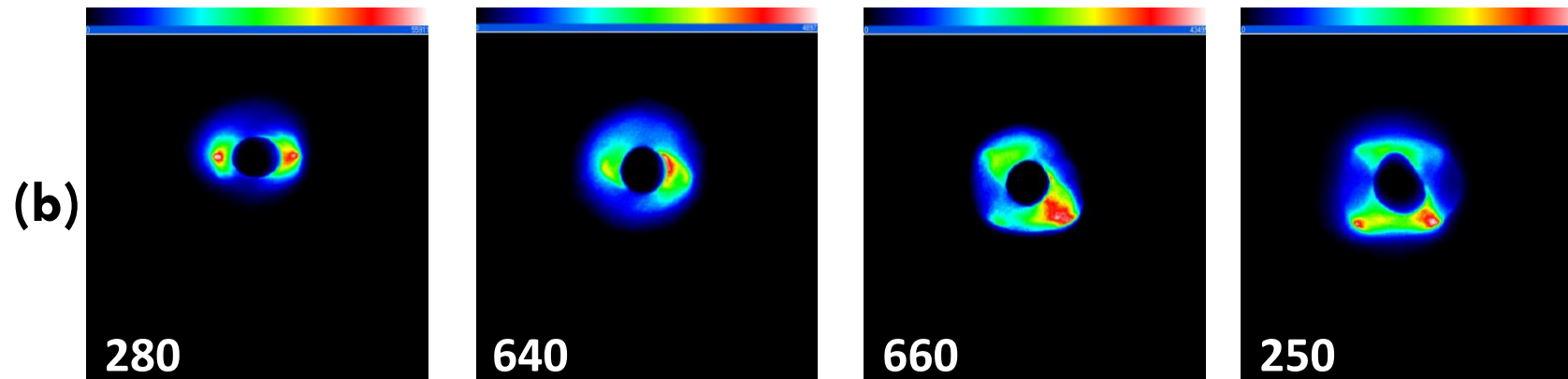
C.P. Welsch et al.,  
Proc. SPIE (2007)  
J. Egberts, et al.,  
JINST **5**P04010 (2010)  
H. Zhang, et al.,  
Phys. Rev. STAB **15** (2012)  
B. Lomberg, et al.  
Proc. IBIC (2013)



Quadrupole  
Current



Different Beam / Different Mask Shape



6mA beam



- Without beam diagnostics
  - it is not possible to even operate a accelerator!!
- Non-invasive, single shot, real-time measurement is demanded.
- New concept adapted from other field is hugely popular
  - ▣ Example: laser, non-linear optics, advanced algorithm, machine learning,...
- User-based development specifically target to project
  - ▣ OMA, AWA, EuPRAXIA, EuroCirCol, AWAKE, HLLHC, etc. projects

Also: Good prospects for commercialization (D:Beam).

# Any Question?

- Workshops, conference and schools
  - BIW, IBIC
  - DITANET, OPAC, USPAS, JUAS, JAS, CAS
- J. Harasimowicz et al., Rev. Sci. Instr. 81 (10), 2010
- H. Koziol, BEAM DIAGNOSTICS FOR ACCELERATORS
- P. Forck, Lecture Notes on Beam Instrumentation and Diagnostics, Joint University Accelerator School, January – March 2012
- J. Hunts, et al., NIMA, Vol 896, Pages 139-151.
- U. Raich, Accelerator Beam Diagnostics, USPAS, Albuquerque NM, June 23-26, 2009
- D. Stratakis, R.A. Kishek, S. Bernal, et al., Physics of Plasmas 17, 056701 (2010)
- H. Zhang, PhD thesis, university of Maryland, 2014
- E. Bravin, Cern Accelerator School on Beam Instrumentation 2-15 June 2018, Tuusula, Finland
- C. Welsch, Beam Diagnostics, CIPAS, 2015
- J. Harasimowicz, et al., PRSTAB, 15, 122801 (2012)
- S. Bernal, Emittance and Emittance Measurements, USPAS08, Beam Dynamics Experiments on the University of Maryland Electron Ring